

Final Report:

APMP.EM-S7

APMP Supplementary Comparison of Capacitance at 100 pF

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Contents

1	Introduction	4
2	Participants and organisation of the comparison	5
2.1	List of participants	5
2.2	Comparison schedule	5
2.3	Organisation of the comparison	5
2.4	Unexpected incidents	6
3	Travelling standard and measurement instructions	7
3.1	Description of the standards	7
3.2	Quantities to be measured and conditions of measurements	7
3.3	Measurement instructions	7
3.4	Deviations from the protocol	7
4	Methods of measurement	8
5	Measurements of the pilot laboratory	9
5.1	Sensitivity of the travelling standards	9
5.2	Stability of the travelling standards	9
5.3	Calculation of reference values	10
6	Measurement results	12
6.1	Normalisation of results	12
6.2	Results of the participating institutes	12
6.3	Calculation of the reference value and its uncertainty	13
6.4	Degrees of equivalence with respect to the comparison value	13
7	Withdrawals or changes of results	15
8	Requests for follow up bilateral comparisons	15
9	Summary and conclusions	15
10	Appendices	16
	Appendix A: Methods of measurement	16
A.1	Method of measurement: CMS, Taiwan	16
A.2	Method of measurement: KIM-LIPI, Indonesia	16
A.3	Method of measurement: KRISS, Korea	17
A.4	Method of measurement: NIM, China	18
A.5	Method of measurement: NIMT, Thailand	18
A.6	Method of measurement: NMI, Australia	19
A.7	Method of measurement: NMIJ/AIST, Japan	19
A.8	Method of measurement: NMISA, South Africa	19
A.9	Method of measurement: NPL, India	20
A.10	Method of measurement: SCL, Hong Kong	20
A.11	Method of measurement: SIRIM, Malaysia	20
A.12	Method of measurement: SPRING, Singapore	21
A.13	Method of measurement: VNIIM, Russia	21
	Appendix B: Uncertainty statements	23
B.1	Uncertainty statement: CMS, Taiwan	23

B.2	Uncertainty statement: KIM-LIPI, Indonesia	23
B.3	Uncertainty statement: KRISS, Korea	24
B.4	Uncertainty statement: NIM, China	24
B.5	Uncertainty statement: NIMT, Thailand	25
B.6	Uncertainty statement: NMI, Australia	26
B.7	Uncertainty statement: NMIJ/AIST, Japan	27
B.8	Uncertainty statement: NMISA, South Africa	27
B.9	Uncertainty statement: NPL, India	28
B.10	Uncertainty statement: SCL, Hong Kong	29
B.11	Uncertainty statement: SIRIM, Malaysia	29
B.12	Uncertainty statement: SPRING, Singapore	30
B.13	Uncertainty statement: VNIIM, Russia	30
	Appendix C: Optional measurements: Dissipation factor	31
	Appendix D: References	31
	Appendix E: Comparison protocol	32

Figures

Figure 5-1 Repeated measurements of the pilot laboratory at a measurement frequency of 1592 Hz and measuring voltage of 10 Vrms.	10
Figure 6-1 Degrees of equivalence d_i of the participating institutes with respect to the comparison reference value.	14

Tables

Table 2-1 List of participants	5
Table 2-2 Comparison schedule	6
Table 4-1 Participants' method of measurement and traceability.	8
Table 5-1 Values required for calculation of reference values.	11
Table 6-1 Summary of results of participating institutes	12
Table 6-2 Degrees of equivalence of the participating institutes relative to the comparison reference value.	14

1 Introduction

A key comparison of capacitance at 10 pF and a supplementary comparison of capacitance at 100 pF have been conducted between participating APMP member laboratories. The aim of these comparisons is to provide participating laboratories with the opportunity to compare national standards of capacitance within the region, and to support participants' entries in Appendix C of the Mutual Recognition Arrangement [1]. Results of the supplementary comparison are reported here. Results of the key comparison are reported separately.

The Andeen-Hagerling AH11A fused-silica capacitance standards used in this comparison were kindly supplied by the National Metrology Institute of Japan, AIST.

The assistance of the support group (Dr. Sze Wey Chua, SPRING Singapore, Dr Rae Duk Lee, KRISS Korea and Mr Andrew Corney, MSL New Zealand) is gratefully acknowledged.

2 Participants and organisation of the comparison

2.1 List of participants

Thirteen laboratories participated in the comparison, as listed in Table 2-1.

	Organisation	Acronym	State or Economy
1	Center for Measurement Standards	CMS	Taiwan
2	Pusat Penelitian Kalibrasi Instrumentasi Metrologi - LIPI	KIM-LIPI	Indonesia
3	Korea Research Institute of Standards and Science	KRISS	Korea
4	National Institute of Metrology	NIM	China
5	National Institute of Metrology (Thailand)	NIMT	Thailand
6	National Measurement Institute of Australia ¹	NMIA	Australia
7	National Metrology Institute of Japan, AIST	NMIJ/AIST	Japan
8	National Metrology Institute of South Africa ²	NMISA	South Africa
9	National Physical Laboratory	NPLI	India
10	Standards and Calibration Laboratory	SCL	Hong Kong
11	Standards and Industrial Research Institute of Malaysia	SIRIM	Malaysia
12	Standards, Productivity and Innovation Board, Singapore	SPRING	Singapore
13	D. I. Mendeleyev Institute for Metrology	VNIIM	Russia

Table 2-1 List of participants.

2.2 Comparison schedule

The comparison schedule is given in Table 2-2.

2.3 Organisation of the comparison

The comparison schedule was initially organised in four consecutive loops (Loops 1 to 4) with between two and four participants in each loop. The artefacts returned to the pilot laboratory, NMIA, for measurement at the conclusion of each loop. Due to concerns about the behaviour of the 10 pF artefact during Loop 1, an additional loop was organised (Loop 5) to allow Loop 1 participants to repeat their measurements of the 10 pF artefact and, optionally, of the 100 pF artefact. Where participants made two measurements of the 100 pF artefact, they were asked to indicate which results was to be reported in the comparison report.

A total of four weeks was scheduled for each participant. Generally participants had at least two weeks and usually three weeks in which to make their measurements, depending on the time taken to clear the artefacts through the customs service in their country and allow the artefacts to settle in their laboratory.

The artefacts were transported in an aluminium case by air using an ATA Carnet for customs clearance where possible. A shock monitor was attached to the outside of the transport case and to the back panel of the artefact enclosure.

¹ Formerly National Measurement Laboratory, CSIRO (CSIRO-NML)

² Formerly National Measurement Laboratory, CSIR (CSIR-NML)

Loop No.	Participant	Standards in laboratory		Mean measurement date(s)	Comments
		From:	To:		
-	NMIA	28 Apr 2003	05 Jan 2004	14 Jun 2003 10 Sep 2003 16 Dec 2003	Initial characterisation of standards.
1	NMIJ/AIST	16 Jan 2004	06 Feb 2004	27 Jan 2004	
1	KRISS	17 Feb 2004	04 Mar 2004	27 Feb 2004 (10 pF) 23 Feb 2004 (100 pF)	Observed step change of 0.2 $\mu\text{F}/\text{F}$ in value of 100 pF on 26 Feb 2006.
1	SPRING	10 Mar 2004	05 Apr 2004	26 Mar 2004(a) 28 Mar 2004(b)	(a) 1000 Hz (b) 1592 Hz
1	CMS	09 Apr 2004	06 May 2004	26 Apr 2004	
1	NMIA	10 May 2004	01 Jul 2004	18 May 2004 20 Jun 2004	Second set of measurements taken as change in drift rate of 10 pF capacitor suspected.
2	NPLI	10 Jul 2004	28 Jul 2004	19 Jul 2004	
2	NIMT	10 Aug 2004	23 Aug 2004	16 Aug 2004	
2	NMISA	03 Sep 2004	21 Sep 2004	17 Sep 2004	
2	NMIA	27 Sep 2004	25 Oct 2004	6 Oct 2004	
3	SIRIM	27 Oct 2004	15 Nov 2004	12 Nov 2004	
3	SCL	20 Nov 2004	11 Dec 2004	28 Nov 2004 (10 pF) 27 Nov 2004 (100 pF)	
3	KIM-LIPI	28 Dec 2004	10 Jan 2005	4 Jan 2005	
3	NMIA	20 Jan 2005	7 Mar 2005	03 Feb 2005 26 Feb 2005	
4	NIM	14 Mar 2005	05 Apr 2005	29 Mar 2005	
4	VNIIM	03 Jun 2005	Sep 2005	18 Aug 2005	
4	NMIA	16 Sep 2005	19 Jan 2006	07 Oct 2005 12 Jan 2006	Standards measured at conclusion of Loop 4 and at start of Loop 5.
5	KRISS	02 Feb 2006	21 Feb 2006	11 Feb 2006	
5	SPRING	24 Feb 2006	17 Mar 2006	11 Mar 2006	
5	NMIJ/AIST	26 Mar 2006	14 Apr 2006	4 Apr 2006	
5	CMS	19 Apr 2006	15 May 2006	8 May 2006	
5	NMIA	22 May 2006		27 May 2006	

Table 2-2 Comparison schedule

2.4 Unexpected incidents

A number of unexpected incidents occurred during the course of the comparison:

- Non-steady behaviour of 10 pF artefact necessitating repetition of Loop 1. Note that the 100 pF artefact did not show any significant deviations from a steady linear drift rate during the whole of the comparison.
- A four month delay to the comparison schedule occurred in Loop 4 during the measurement period assigned to VNIIM. This was in addition to the extra four weeks that was allowed for customs clearance in and out of Russia.
- The shock monitor attached to the outside of the transport case was activated during shipment from KRISS to SPRING in Loop 5. The shock monitor attached to the back panel of the artefact enclosure was not activated. No damage to the artefacts or changes in behaviour of the artefacts was noted.

3 Travelling standard and measurement instructions

3.1 Description of the standards

The travelling standard was a 100 pF Andeen-Hagerling AH11A fused silica capacitance standard mounted in a AH1100 capacitance standard frame. A second Andeen-Hagerling AH11A fused silica capacitance standard mounted in the same AH1100 capacitance standard frame was used for the key comparison at 10 pF (reported separately). The AH1100 frame is a standard-width bench-top or rack-mountable frame. The AH11A capacitance standard includes a temperature-controlled oven that is powered via the AH1100 frame. The frame also monitors internal power voltages and temperatures.

The capacitor is fitted with BNC co-axial terminations. Co-axial measuring leads with BNC to MUSA connectors were supplied with the capacitor, together with MUSA-GR874 adapters and MUSA-BNC adapters.

3.2 Quantities to be measured and conditions of measurements

The measured quantity was the capacitance of the capacitor **at the terminals on the AH1100 frame**. The preferred measuring voltage was 100 V(rms). The preferred measurement frequency was 1592 Hz ($\omega = 10^4 \text{ rad}\cdot\text{s}^{-1}$). Measurements at a frequency of 1000 Hz were permitted instead of, or as well as, 1592 Hz. Measurement of the dissipation factor was optional.

The comparison measurand m_n is defined as the n th comparison measurement of the fractional difference of the measured capacitance, C_n , from the nominal value of the capacitor, C , calculated as:

$$m_n = \frac{C_n}{C} - 1. \quad (1)$$

The subscript n denoting the measurement number should not be confused with the subscript i , which is introduced in Section 6.4 and denotes the participating laboratory.

Participants were asked to report the drift and chassis temperature readings for each capacitor, and the ambient temperature, for monitoring purposes.

3.3 Measurement instructions

The AH 1100/11A Operation and Maintenance Manual was included with the shipment of the travelling standards. The comparison protocol encouraged participants to leave the standards to stabilise for two to three days before measurement.

3.4 Deviations from the protocol

There were no deviations from the protocol.

4 Methods of measurement

Table 4-1 lists the method of measurement used by each participant and the traceability route to the SI. Further details are given in Appendix A.

Participant	Traceability	Measurement Method		
		Bridge	Technique	Reference standard
CMS	DC QHR	10:1 ratio transformer (4TP)	Comparison	1000 pF
KIM-LIPI	NMIA (Melbourne Branch)	GR1621A	Comparison	100 pF
KRISS	BIPM [†] , CENAM [‡] , NIST [§] , NMIA, VNIIM	10:1 ratio transformer	Comparison	10 pF
NIM	Calculable capacitor	1:1 ratio transformer	Comparison	100 pF
NIMT	PTB ^{**}	GR1620	Comparison	100 pF
NMIA	Calculable capacitor	10:1 ratio transformer	Substitution	100 pF
NMIJ/AIST	DC QHR	Capacitance bridge (2TP)	Substitution	100 pF
NMISA	BIPM [†]	AH2500A	Substitution	100 pF
NPLI	Calculable capacitor	10 V: 10:1 ratio transformer	Comparison	10 pF
		100 V: IET Labs 1621	Substitution	100 pF
SCL	NPL [*]	AH2500A	Substitution	100 pF
SIRIM	BIPM [†]	GR1615A	Comparison	100 pF
SPRING	NPL [*]	GR1621A	Substitution	100 pF
VNIIM	Calculable capacitor	10:1 ratio transformer	Comparison	10 pF

Table 4-1 Participants' method of measurement and traceability.

[†] International Bureau of Weights and Measures

[‡] Centro Nacional de Metrologia, Mexico.

[§] National Institute of Standards and Technology, USA

^{*} National Physical Laboratory, UK.

^{**} Physikalisch Technische Bundesanstalt, Germany

5 Measurements of the pilot laboratory

Measurements made by the pilot laboratory were used to assess the stability of the travelling standards during the course of the comparison. Assessment of the sensitivity of the standards to ambient temperature, temperature cycling, measurement voltage, and measurement frequency was based on the manufacturer's specifications as well as pilot laboratory measurements.

5.1 Sensitivity of the travelling standards

AH11A capacitance standards have a low sensitivity to changes in ambient temperature due to an internal temperature-controlled oven. The manufacturer's specification for the temperature coefficient with respect to changes in ambient temperature is $0.01 \mu\text{F}/\text{F } ^\circ\text{C}^{-1}$. Pilot laboratory measurements confirm that the temperature coefficient for the travelling standard is no greater than this value. The protocol requested participants not to make corrections for ambient laboratory temperature, but suggested that an uncertainty component for ambient laboratory temperatures differing from $20 \text{ }^\circ\text{C}$ could be included in the uncertainty statement.

The manufacturer's specification for the sensitivity of the AH11A standards to temperature cycling and to mechanical shock is $0.05 \mu\text{F}/\text{F}$. Temperature cycling of the travelling standard under laboratory conditions by the pilot laboratory caused changes of this order of magnitude. The travelling standard was shipped un-powered in all cases so that hysteresis due to temperature cycling and to mechanical shock contributes to the scatter in the measurements of the pilot laboratory and need not be separately treated.

The manufacturer's specification for the sensitivity of the AH11A standards to ac measurement voltage is $0.003 \mu\text{F}/\text{F } \text{V}^{-1}$ at 1 kHz. Pilot laboratory measurements of the travelling standard at 1592 Hz could not detect a sensitivity to measurement voltage. We conclude that the sensitivity of the travelling standard to ac measurement voltage is less than $0.0003 \mu\text{F}/\text{F } \text{V}^{-1}$ at 1592 Hz. No correction is made to measurements made at voltages other than the $100 \text{ V}_{\text{rms}}$ specified in the comparison protocol, but an uncertainty component is included where appropriate.

The capacitance change when the frequency is increased from 1000 Hz to 1592 Hz was measured by the pilot laboratory to be $-0.033 \mu\text{F}/\text{F}$ with a standard uncertainty of $0.013 \mu\text{F}/\text{F}$.

5.2 Stability of the travelling standards

Measurements by the pilot laboratory were made at 1592 Hz before the start of the comparison and at the conclusion of each measurement loop. Pilot laboratory measurements at 1592 Hz are listed in Table 6-1 and plotted in Figure 5-1. Weighted linear regression using the standard uncertainty of the measurement as weight was performed on each set of data (refer to Table 5-1 for details of the fit parameters). The Birge ratio, R_B , is a measure of self-consistency in a set of measurements (see, for example, [2]). The value computed for the pilot laboratory dataset was $R_B = 0.8$ with $u(R_B) = 0.3$. It is concluded that the criterion for self consistency, $R_B = 1 \pm u(R_B)$, is met, and that the behaviour of the standard can be adequately described by a linear drift with time.

Additional measurements made by the pilot laboratory of the frequency difference are used to derive reference values at 1000 Hz using the drift rate determined at 1592 Hz.

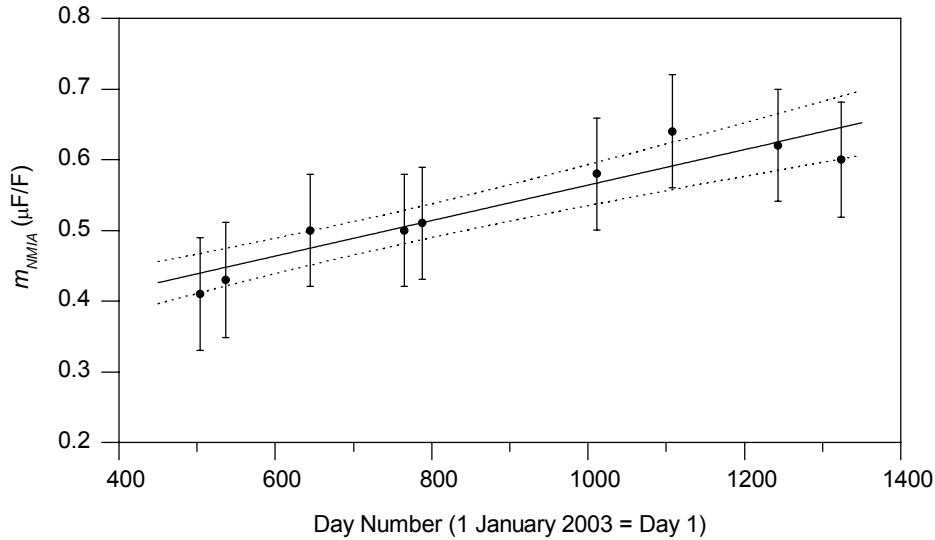


Figure 5-1 Repeated measurements of the pilot laboratory at a measurement frequency of 1592 Hz and measuring voltage of 10 Vrms.

Uncertainty bars represent expanded uncertainty. Solid line: line of best fit (weighted linear regression), dashed lines: prediction bands (expanded uncertainty of predicted values).

5.3 Calculation of reference values

The predicted or reference value, p_n , for each capacitor at the time of the n th measurement is calculated as:

$$p_n = a_0 + a_1 t_n + a_2 \left(\frac{1592 - f_n}{1592 - 1000} \right) + a_3 + a_4 \quad (2)$$

where a_0 and a_1 are determined from the weighted linear regression described in Section 5.2, a_2 is related to the frequency coefficient of capacitance, a_3 is the correction to ambient temperature of 20 °C, a_4 is the correction to a measurement voltage of 100 V_{rms}, t_n is the time of the n th measurement and f_n is the measurement frequency (in Hz) for the n th measurement. Note that a_3 and a_4 are taken to be zero. The uncertainty in the reference value is calculated as:

$$u^2(p_n) = u^2(a_0) + u^2(a_1) \cdot t_n^2 + 2 \cdot \text{cov}(a_0, a_1) \cdot t_n + s^2 + u^2(a_2) \cdot \left(\frac{1592 - f_n}{1592 - 1000} \right)^2 + u^2(a_3) + u^2(a_4) \cdot \left(\frac{100 - V_{PL}}{100 - 10} \right)^2 \quad (3)$$

where $\text{cov}(a_0, a_1)$ is the mutual covariance of a_0 and a_1 , s^2 is the unbiased estimate of the population variance σ^2 of the residuals of the weighted linear regression, V_{PL} is the rms measurement voltage of the pilot laboratory and the uncertainties $u(t_n)$ and $u(f_n)$ are assumed to be negligible. Note that the first four terms of (3) are derived from the linear fit to the pilot laboratory measurements and terms five and seven relate to the frequency and voltage coefficients respectively. Term 6 is the uncertainty in realising an ambient temperature of 20 °C in the pilot laboratory measurements.

The number of degrees of freedom for the reference value is calculated as:

$$v(p_n) = \frac{u^4(p_n)}{\frac{(u^2(a_0) + u^2(a_1) \cdot t_n^2 + 2 \cdot \text{cov}(a_0, a_1) \cdot t_n + s^2)^2}{l-2} + \frac{u^4(a_2) \left(\frac{1592 - f_n}{1592 - 1000}\right)^4}{v(a_2)} + \frac{u^4(a_3)}{v(a_3)} + \frac{u^4(a_4) \left(\frac{100 - V_{PL}}{100 - 10}\right)^4}{v(a_4)}} \quad (4)$$

where l is the number of measurements used to calculate the weighted linear regression. The values of constants required for the calculation of the reference values and their uncertainty are listed in Table 5-1.

Quantity	Value	Standard uncertainty	Degrees of freedom
C_{nom}	100 pF	-	-
V_{PL}	10 V	-	-
a_0	0.313 $\mu\text{F}/\text{F}$	0.024 $\mu\text{F}/\text{F}$	10
a_1	2.51×10^{-4} $\mu\text{F}/\text{F}$ per day	0.29×10^{-4} $\mu\text{F}/\text{F}$ per day	10
$\text{cov}(a_0, a_1)$	-0.60×10^{-6} ($\mu\text{F}/\text{F}$) ² per day	-	-
s	1.81×10^{-3} $\mu\text{F}/\text{F}$	-	-
a_2	0.033 $\mu\text{F}/\text{F}$	0.013 $\mu\text{F}/\text{F}$	19
a_3	0 $\mu\text{F}/\text{F}$	3.7×10^{-3} $\mu\text{F}/\text{F}$	8
a_4	0.000 $\mu\text{F}/\text{F}$ V^{-1}	0.006 $\mu\text{F}/\text{F}$ V^{-1}	200

Table 5-1 Values required for calculation of reference values.

6 Measurement results

6.1 Normalisation of results

Participants' measurements were treated to account for the effect of drift and measurement conditions by subtracting the reference value for the artefact at the time of the n th measurement from the measured value m_n to give a corrected measurement value x_n , that is

$$x_n = m_n - p_n \quad (5)$$

The uncertainty in the corrected measurement value $u(x_n)$ and the associated number of degrees of freedom $\nu(x_n)$ are calculated in accordance with the ISO "Guide to the expression of uncertainty in measurement, 1st ed."

6.2 Results of the participating institutes

n	Participant	Date	f	V_{rms}	m_n	$u(m_n)$	$\nu(m_n)$	p_n	$u(p_n)$	$\nu(p_n)$	x_n	$u(x_n)$	$\nu(x_n)$
		dd/mm/yy	(Hz)	(V)	($\mu\text{F}/\text{F}$)	($\mu\text{F}/\text{F}$)		($\mu\text{F}/\text{F}$)	($\mu\text{F}/\text{F}$)		($\mu\text{F}/\text{F}$)	($\mu\text{F}/\text{F}$)	
1	NMIA	15/06/03	1592	10	0.330	0.038	12	0.355	0.020	12	-0.025	0.043	18
2	NMIA	10/09/03	1592	10	0.360	0.036	10	0.377	0.018	13	-0.017	0.040	15
3	NMIA	16/12/03	1592	10	0.460	0.037	11	0.401	0.016	13	0.059	0.040	15
4	NMIJ/AIST	27/01/04	1592	100	0.426	0.036	2277	0.412	0.016	14	0.014	0.039	474
5	NMIA	18/05/04	1592	10	0.410	0.036	11	0.440	0.014	15	-0.030	0.039	14
6	NMIA	20/06/04	1592	10	0.430	0.037	11	0.448	0.013	16	-0.018	0.039	14
7	NPLI	19/07/04	1000	100	-1.370	1.100	988	0.489	0.018	35	-1.859	1.100	989
8	NPLI	19/07/04	1592	100	-0.670	1.050	840	0.456	0.013	16	-1.126	1.050	840
9	NPLI	19/07/04	1000	10	-1.320	0.400	514	0.489	0.018	35	-1.809	0.400	516
10	NPLI	19/07/04	1592	10	-0.680	0.400	1028	0.456	0.013	16	-1.136	0.400	1030
11	NIMT	16/08/04	1000	100	1.300	0.860	168	0.496	0.018	35	0.804	0.860	168
12	NMISA	17/09/04	1000	10	0.510	0.053	4.7×10^9	0.504	0.018	36	0.006	0.056	3320
13	NMIA	06/10/04	1592	10	0.500	0.035	9	0.475	0.012	17	0.025	0.037	11
14	SIRIM	08/11/04	1000	10	1.500	0.853	139	0.517	0.018	36	0.983	0.853	139
15	SCL	27/11/04	1000	7.5	2.000	2.1	223	0.521	0.018	36	1.479	2.100	223
16	KIM-LIPI	04/01/05	1592	100	0.500	5.99	2.6×10^7	0.498	0.012	17	0.002	5.990	2.6×10^7
17	NMIA	03/02/05	1592	10	0.500	0.035	9	0.506	0.012	17	-0.006	0.037	11
18	NMIA	26/02/05	1592	10	0.510	0.035	9	0.511	0.012	17	-0.001	0.037	11
19	NIM	29/03/05	1592	10	0.573	0.11	1×10^9	0.519	0.012	17	0.054	0.111	1×10^5
20	VNIIM	18/08/05	1000	9.85	0.370	0.198	39	0.588	0.019	33	-0.218	0.199	40
21	NMIA	07/10/05	1592	10	0.580	0.035	9	0.567	0.014	15	0.013	0.038	12
22	NMIA	12/01/06	1592	10	0.640	0.036	10	0.592	0.016	13	0.048	0.039	14
23	KRISS	11/02/06	1000	10	0.490	0.106	16	0.632	0.021	27	-0.142	0.108	17
24	KRISS	11/02/06	1592	10	0.470	0.109	17	0.599	0.017	13	-0.129	0.110	18
25	SPRING	11/03/06	1000	10	1.100	0.54	1.9×10^8	0.639	0.022	26	0.461	0.540	9.6×10^6
26	SPRING	11/03/06	1592	10	1.100	0.54	1.2×10^8	0.606	0.017	13	0.494	0.540	1.1×10^8
27	CMS	08/05/06	1592	60	0.780	0.08	3.9×10^5	0.621	0.019	12	0.159	0.082	4744
28	NMIA	27/05/06	1592	10	0.620	0.035	9	0.626	0.019	12	-0.006	0.040	14
29	NMIA	16/08/06	1592	10	0.600	0.037	11	0.646	0.021	12	-0.046	0.042	17

Table 6-1 Summary of results of participating institutes. See text for definition of symbols.

6.3 Calculation of the reference value and its uncertainty

Although a comparison reference value is not required for regional supplementary comparisons, it is useful to define a reference value for transparency of presentation and calculation.

The comparison reference value is taken to be $x_{ref} = 0 \mu\text{F}/\text{F}$ with standard uncertainty of $u(x_{ref}) = 0 \mu\text{F}/\text{F}$ with the concurrence of all participants. Note that the choice of reference value does not affect the principal results of this comparison, that is, the pair-wise degrees of equivalence.

Other choices considered for the comparison reference value were:

1. Simple weighted mean of all results not previously identified as discrepant,
2. Generalised weighted mean (GWM)¹ of all results not previously identified as discrepant,
3. GWM of results from laboratories with an independent realisation of the Farad, and
4. GWM of pilot laboratory measurements.

In all cases the calculated mean was within a few parts in 10^8 of $x_{ref} = 0 \mu\text{F}/\text{F}$ with an uncertainty less than $0.05 \mu\text{F}/\text{F}$.

6.4 Degrees of equivalence with respect to the comparison value

Degrees of equivalence with respect to the comparison reference value are reported in this section. Only one value is reported for each participating laboratory. Where laboratories made more than one measurement the following selection criteria are applied:

1. If measurements were made at both 1592 Hz and 1000 Hz, degrees of equivalence are reported with respect to the measurement at 1592 Hz.
2. If measurements were made at more than one measurement voltage, degrees of equivalence are reported with respect to the measurement made at the measurement voltage closest to 100 V_{rms} .
3. For the pilot laboratory, degrees of equivalence are reported with respect to a generalised weighted mean of all pilot laboratory measurements.

For simplicity of notation, the subscript identifying the measurement number (n) is omitted in this section.

The degree of equivalence of the i th participant with respect to the comparison reference value is calculated as

$$d_i = x_i - x_{ref} = x_i. \quad (6)$$

The expanded uncertainty associated with this result, $U(d_i)$, is calculated as $U(d_i) = k_i u(x_i)$ where k_i is chosen to give 95 % coverage based on $u(x_i)$. The degrees of equivalence of the participating institutes relative to the comparison reference value are tabulated in Table 6-2 and represented graphically in Figure 6-1.

¹ A weighted mean including treatment of inter- and intra-laboratory correlations.

Participant	d_i ($\mu\text{F}/\text{F}$)	$U(d_i)$ ($\mu\text{F}/\text{F}$)
CMS	0.159	0.161
KIM-LIPI	0.002	11.740
KRISS	-0.129	0.232
NIM	0.054	0.217
NIMT*	0.804	1.698
NMIA	0.002	0.037
NMIJ/AIST	0.014	0.077
NMISA*	0.006	0.110
NPLI	-1.126	2.061
SCL*	1.479	4.139
SIRIM*	0.983	1.687
SPRING	0.494	1.059
VNIIM*	-0.218	0.402

Table 6-2 Degrees of equivalence of the participating institutes relative to the comparison reference value.
 *Measurements made at a frequency of 1000 Hz (all other measurements at 1592 Hz).

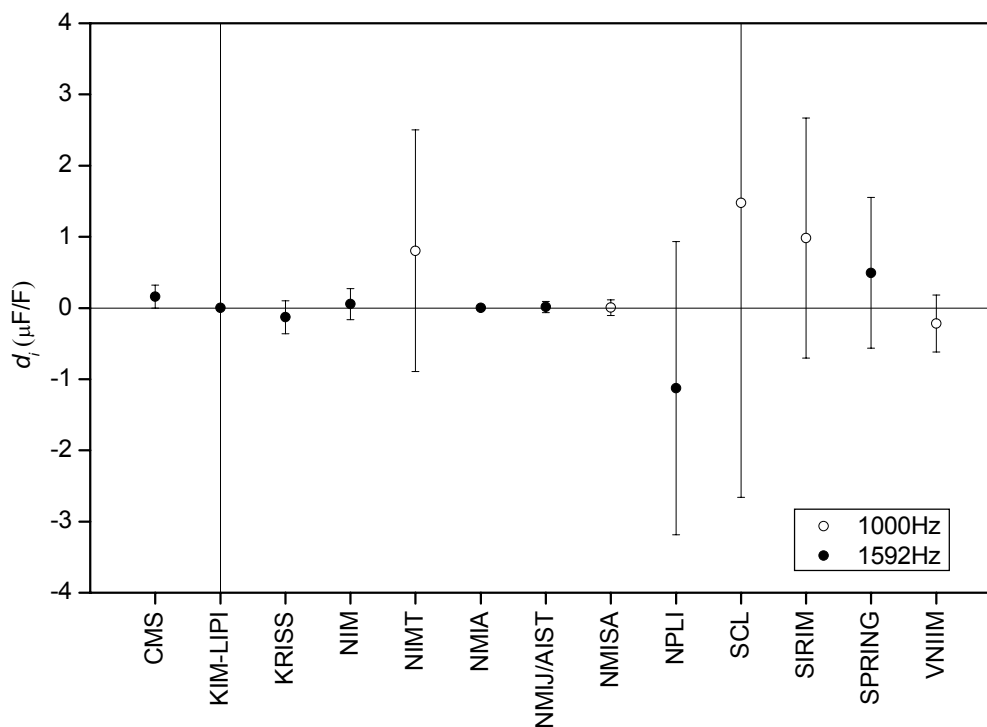


Figure 6-1 Degrees of equivalence d_i of the participating institutes with respect to the comparison reference value.

Uncertainty bars represent the expanded uncertainty $U(d_i)$.

7 Withdrawals or changes of results

The Measurement Standards Laboratory, Industrial Research Limited, New Zealand were unable to measure the capacitance standards due to unexpected circumstances and withdrew from the comparison before their scheduled measurements.

8 Requests for follow up bilateral comparisons

MSL, New Zealand and NPL, India have indicated that they may wish to participate in bilateral comparisons in the future.

9 Summary and conclusions

A supplementary comparison of capacitance at 100 pF has been conducted between participating APMP member laboratories. There is good agreement between participating laboratories in the region for this quantity. It is expected that this comparison will be able to provide support for participants' entries in Appendix C of the Mutual Recognition Arrangement.

10 Appendices

Appendix A: *Methods of measurement*

Details of the method of measurement and traceability to the SI, as reported by participants, are reproduced below. Note that information relating to the key comparison APMP.EM-K4.1, conducted at the same time as APMP.EM-S7, is included in some cases as the protocol did not require participants to describe their method of measurement separately.

A.1 *Method of measurement: CMS, Taiwan*

The comparison artefacts, 10 pF and 100 pF capacitors, are compared to 1000 pF reference standards individually by the 10:1 four terminal-pair (4TP) coaxial transformer bridge.

The 1000 pF reference standard is GR1404A air standard capacitor which is traceable to DC quantum Hall resistance of CMS through ac resistance standards by using the quadrature bridge.

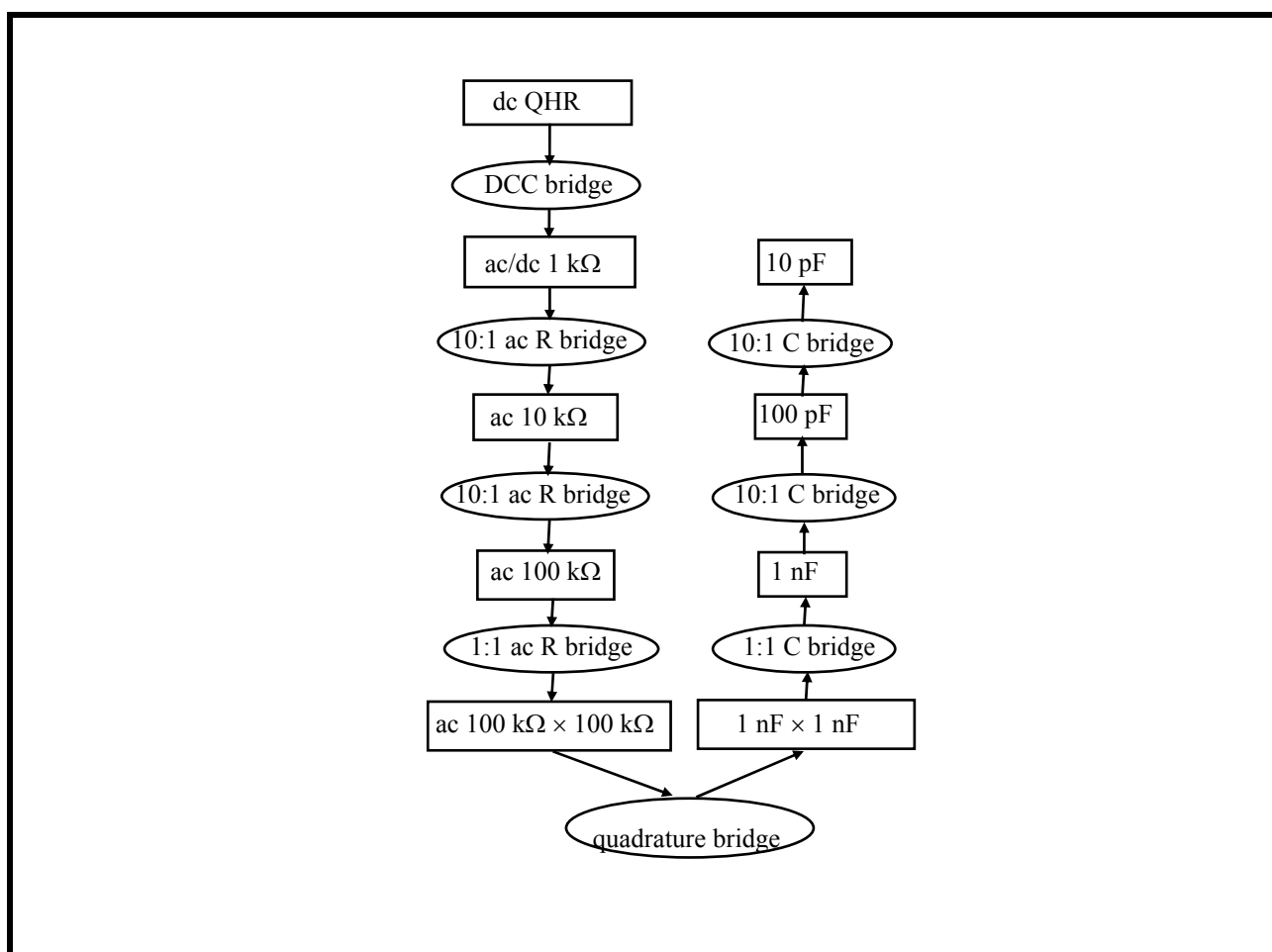


Figure A - 1 CMS Traceability to the SI.

A.2 *Method of measurement: KIM-LIPI, Indonesia*

Facilities:

- Standard Capacitor GR-1404B (100pF): as reference.
- Capacitance Measurement System GR-1621: as comparator.

-Thermo-Hygrometer Corona GL-89.

Methodology:

-Artefact (10pF & 100pF) was compared to reference capacitor (100pF), and used Capacitance Measurement System GR-1621 with ratio 1:1 and 1:10.

-Measurement or comparison was repeated 10 times.

-Capacitor or room temperature was measured during artefact measurements.

A.3 Method of measurement: KRISS, Korea

For the key and supplementary comparisons, a 10:1 ratio transformer bridge (see Figure A - 2) developed by a joint work between NMIA and KRISS was used.

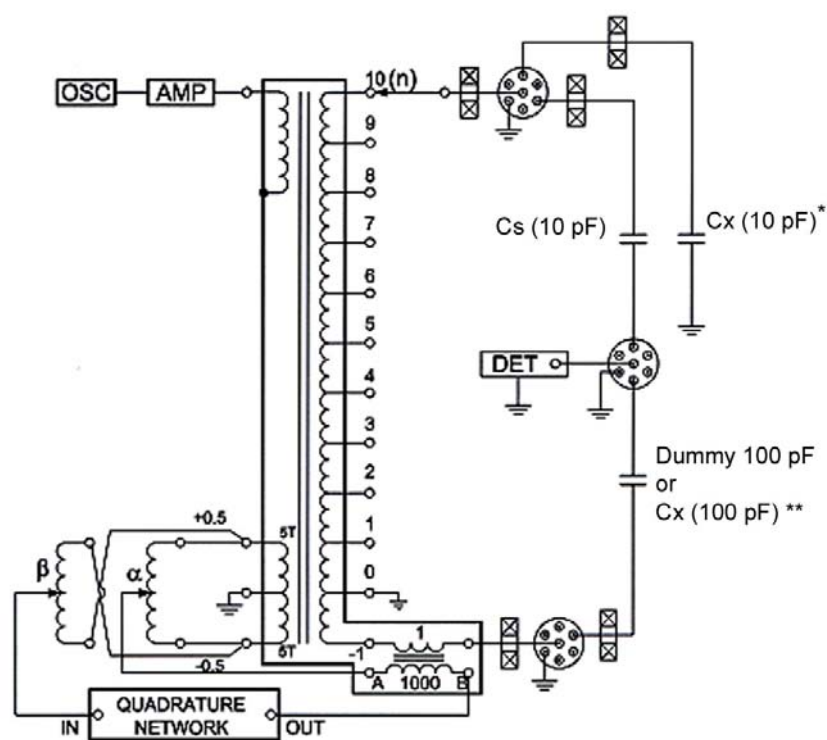


Figure A - 2 KRISS 10:1 ratio transformer bridge

For the 10 pF (*) capacitor, it was measured by a substitution method between a 10 pF Zerodur standard capacitor and the 10 pF A/H capacitor, $C_x(10 \text{ pF})^*$. And for 100 pF A/H capacitor (**), it was measured by 10:1 comparison method after disconnecting the $C_x(10 \text{ pF})^*$.

As a calculable cross capacitor and toroidal cross capacitors have been developed at KRISS and are under analytical evaluation, the KRISS national standard of capacitance has been maintained using a 10 pF Zerodur capacitor developed in 1985 by a joint work between NMIA and KRISS. Since 1987, some of bilateral comparisons between NMIA and KRISS were carried out. In 1996 the value of standard was corrected by an inter-comparison among NMIA, KRISS and VNIIM. Continuously, this standard value has been traced through a comparison between BIPM and KRISS using a KLR standard capacitor developed at KRISS. After that, since 2002, not only a Zerodur capacitor but also a group of KLR capacitors are maintained as capacitance standard of KRISS.

Recently a bilateral comparison between KRISS and CENAM was carried out by using A/H capacitors, and then the results have been re-confirmed through calibration at BIPM for the same capacitors.

The value for the KRISS reference standard is derived from an extrapolation of a quadratic least squares fit to seven data points based on the following measurements:

- [1] On May 1987, the 10 pF Zerodur capacitor (s/n S-65146), maintenance standard, was compared with another 10 pF Zerodur capacitor (s/n S-65145) calibrated by NML CSIRO and hand-carried to the KRISS by Greig Small (uncertainty was evaluated to be 0.5 ppm).
- [2] On November 1991, the same Zerodur capacitor (s/n S-65146) was hand-carried by Raeduk LEE to NMIA, and compared again with uncertainty 0.5 ppm.
- [3] On April 1995, a bilateral comparison between KRISS, NMIA and VNIIM was carried out by using two 10 pF fused silica capacitors (KKC-1, #4 and #8) as a travelling standard (uncertainty was less than 0.1 ppm).
- [4] On July 1999, a bilateral comparison between KRISS and VNIIM participated to the CCEM KC was carried out again by using the same fused silica capacitor KKC-1, #8 (uncertainty was less than 0.1 ppm).
- [5] On June 2001, a 10 pF KLR capacitor (s/n 12/12) developed by Raeduk LEE was hand-carried to BIPM, and re-confirmed the KRISS standard value with uncertainty less than 0.1 ppm.
- [6] On July 2003, a bilateral comparison between KRISS, CENAM was carried out by using A/H 11A, then the same A/H capacitor was measured at BIPM (uncertainty was less than 0.1 ppm).
- [7] On May 2005, a bilateral comparison between KRISS and NIST was carried out by using the same KLR capacitor, s/n 12/12 (uncertainty was less than 0.1 ppm).

A.4 Method of measurement: NIM, China

The national capacitance standard was established in NIM in 1982. The essential part of this standard is a calculable capacitor of Thompson-Lampard type. The nominal value of the calculable capacitor is 0.5 pF and the uncertainty is 1×10^{-7} . The main source of the uncertainty is from the axial length determination of the capacitor.

A transformer bridge is prepared for the capacitance comparison. The ratio of the bridge is 1:1, 1:2, 1:5 and 1:10. The uncertainty of the comparison is 3×10^{-9} .

The working capacitance standard is a set of 10 pF and 100 pF fused silica capacitors. The values of the working capacitance standard are determined by the calculable capacitor periodically. The uncertainty of the value of the working standard is 0.11 ppm. The APMP Key comparison of capacitance at 10 pF and the APMP supplementary comparison of capacitance at 100 pF are completed by direct comparison of the travelling standard to the working standard of capacitance.

A.5 Method of measurement: NIMT, Thailand

The fused silica capacitance standard, Capacitor A (B), was measured by using null method with the capacitance bridge, GR 1620 and the NIMT reference standard capacitor GR1404 C

(GR1404 B). At balance, the value of the said capacitance is the value of the reference standard capacitor multiplied by the bridge ratio.

The measurement is traceable to the Physikalisch-Technische Bundesanstalt (PTB), Germany through PTB Certificate No. 2339 PTB 03, 2338 PTB 03 and 2337 PTB 03.

A.6 Method of measurement: NMI, Australia

The NMIA derives its capacitance standard from a Thompson-Lampard calculable capacitor [3-6] traceable to the SI via NMIA's length standard.

The Calculable Capacitor ($\frac{1}{6}$ pF) is used to measure three $\frac{1}{6}$ pF fixed capacitors by substitution on a transformer ratio bridge.

These three measured capacitors are then connected in parallel to constitute a reference capacitor of nominal value 0.5 pF, that is used on the NMIA 10:1 Transformer Ratio Bridge to measure 5 pF, then 50 pF, reference capacitors.

The measurement sequence linking the 50 pF reference capacitor to the Calculable Capacitor was performed at 1592 Hz within 10 days of each of the reported measurements. The history of the reference capacitor was used to interpolate (or in limited cases, extrapolate) its value, to obtain a value at the time of the reported measurements.

At the time of each independent measurement of the comparison artefacts, the 50 pF reference capacitor (50I) is compared with another 50 pF capacitor (50P) to obtain a 100 pF working standard (50I + 50P)

The comparison artefact, a 100 pF A-H capacitor, is compared with the 100 pF working standard on the same NMI 10:1 Transformer Ratio Bridge by substitution. The known frequency coefficient of the reference capacitor 50I is used to calculate a value for the working standard for measurements at 1000 Hz.

A.7 Method of measurement: NMIJ/AIST, Japan

The capacitance is traceable to the QHR, the value of which was determined based on the latest value of the von Klitzing constant having an uncertainty with respect to the SI.

By using the four terminal-pair resistance bridge, the two terminal-pair quadrature bridge, the two terminal-pair capacitance bridge and the ac/dc calculable resistor, the capacitance was derived from the Quantized Hall Resistance (QHR).

A.8 Method of measurement: NMISA, South Africa

The intercomparison artefacts, a 10 pF AH11A Fused Silica Standard and a 100 pF AH11A Fused Silica Standard were compared to standards of the same type and nominal value, as listed in Table A - 1, by direct substitution using an Andeen-Hagerling 2500 A Ultraprecision Capacitance Bridge, at 1 kHz. The voltages applied to the capacitor by this bridge are not specified, but are limited to about 15 V at 10 pF and 7,5 V at 100 pF. The capacitance was evaluated for a measuring voltage of 10 V by including the uncertainty due to the voltage coefficient of the capacitors. The environmental temperature of the laboratory was 24 °C during the comparison measurements. The capacitance was evaluated for a nominal temperature of 20 °C, by including the uncertainty due to the temperature coefficients of the capacitors. For the evaluations at 100 V, corrections for the values of the capacitors cannot be made, since the actual voltage coefficients of the capacitors are

not known. Therefore we included only an extra uncertainty component based on the manufacturer's specifications for the voltage coefficients of the capacitors.

Description	Make & Model	Serial / ID Number
10 pF Fused Silica Standard	Andeen-Hagerling, AH11A	01286
100 pF Fused Silica Standard	Andeen-Hagerling, AH11A	01287
Ultraprecision Capacitance Bridge	Andeen-Hagerling, AH 2500 A	000 640
Low Noise Coaxial Cable	Andeen-Hagerling, DCOAX	CRN-0241/1

Table A - 1 NMISA reference standards and equipment used.

A.9 Method of measurement: NPL, India

The values of two 10 pF capacitors (one GenRad GR1404-C and one Andeen-Hagerling AH-11A) were derived from the calculable capacitor. Two 100 pF capacitors were measured against these two 10 pF capacitors using a 10:1 bridge and a direct comparison method.

The 10 pF comparison artefact was compared against the two 10 pF capacitors in turn using the 10:1 bridge and a 1:1 substitution method.

At 10 V, the 100 pF comparison artefact was measured against one of the 10 pF capacitors using the 10:1 bridge and a direct comparison method.

At 100 V, the 100 pF comparison artefact was measured against one of the 100 pF capacitors using an IET Labs1621 bridge.

A.10 Method of measurement: SCL, Hong Kong

The capacitance of the test capacitors was determined at 1 kHz by substitution method. The laboratory's reference standard capacitors were first measured using an Andeen-Hagerling capacitance bridge model AH 2500A. The test capacitors were then measured using the same bridge. The difference between the two readings was used, together with the known values of the reference standard capacitors, to calculate the values of the test capacitors.

The two reference standard capacitors (10 pF and 100 pF) were calibrated by NPL, UK for traceability to SI.

A.11 Method of measurement: SIRIM, Malaysia

The 10 pF capacitor was measured by comparison against the 10 pF reference capacitor maintained by the National Metrology Laboratory, Malaysia, at a frequency of 1000 Hz and a voltage of 100 V using the GR 1615A capacitance bridge. See **Error! Reference source not found.**

The 100 pF capacitor was measured by comparison against the 100 pF reference capacitor maintained by the National Metrology Laboratory, Malaysia, at a frequency of 1000 Hz and a voltage of 10 V using the GR 1615A capacitance bridge. See Figure A - 3.

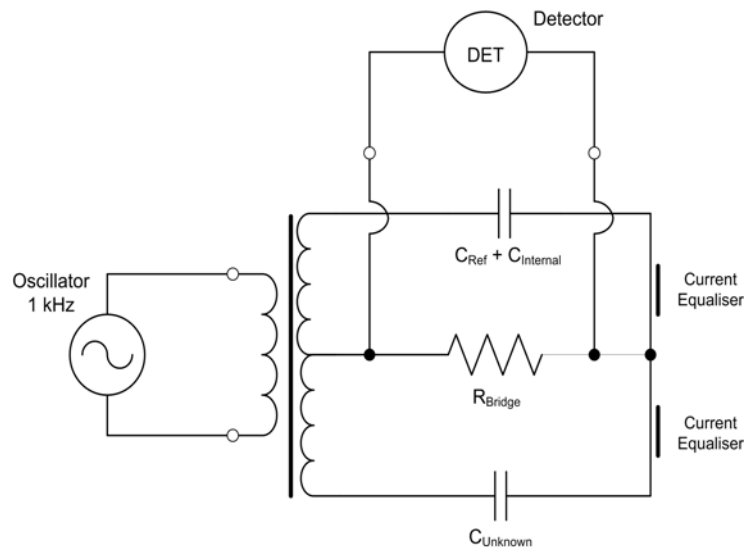


Figure A - 3: SIRIM GR 1615A Bridge configuration for 100 pF measurement at 10 V.

A.12 Method of measurement: SPRING, Singapore

A GenRad (GR) 1621A Precision Capacitance Bridge was used for the measurements of 10 pF and 100 pF travelling capacitance standards at 1 kHz and 1.592 kHz. The GR bridge was used with an external thermostatted fused silica dielectric capacitance standard as a reference capacitor. For the comparison, a substitution method of measurement was used to compare the travelling standards against similar capacitance reference standards, using the GR's external reference capacitor as a 'dummy' standard. The capacitance reference standards have been calibrated with traceability to the unit of capacitance maintained by groups of capacitance standards at 10 pF and 100 pF.

A.13 Method of measurement: VNIIM, Russia

The TO-1 transformer bridge which is a part of the secondary standard of capacitance was used to measure 10 and 100 pF capacitors (simplified circuit diagram is shown in Figure A - 4). Ratio windings of this bridge are executed as copper straps located side by side (the design is similar to that described in [7]) so that the output impedance does not exceed 0.030Ω at 1 kHz. The bridge can be balanced by adjustment of two six-decade IVDs whose outputs are connected in series with the quadrature circuit and the injection transformer.

The 10 pF AH capacitor is measured by means of substitution method with use of 10 pF capacitors from the group standard that maintains the national unit of capacitance.

The 100 pF capacitor is measured using 1/10 ratio of the bridge and the capacitors that are specified above. The 1/10 ratio is calibrated by comparison with the self-calibrated TMK bridge which is a part of the state primary standard of capacitance [8].

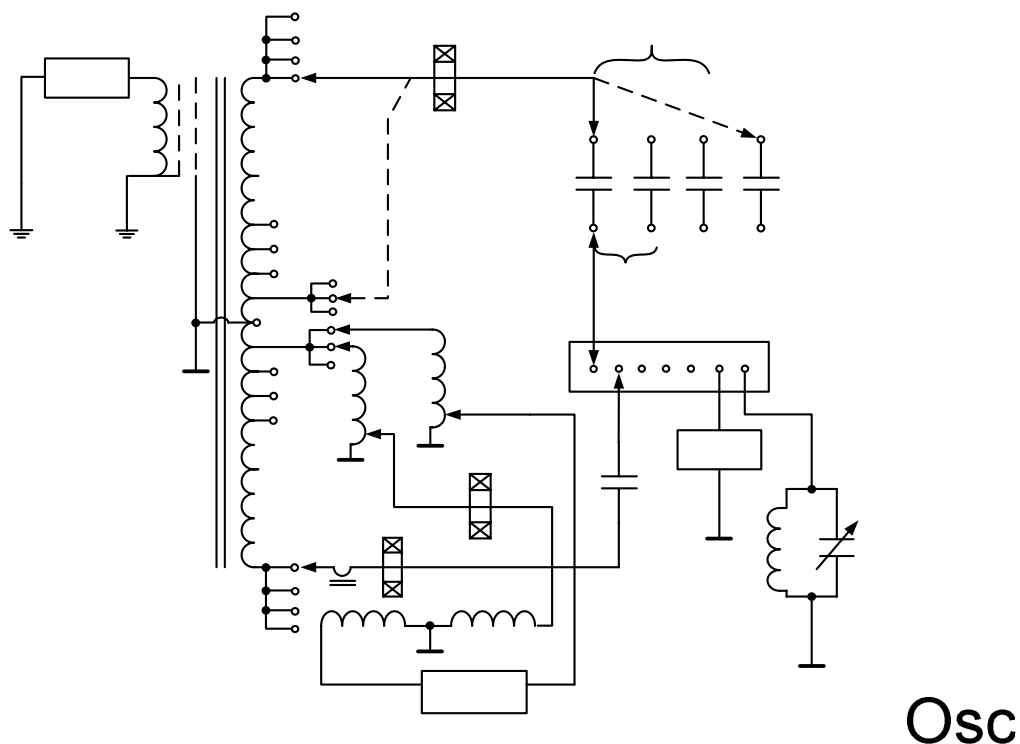


Figure A - 4: VNIIM TO-1 transformer bridge

Traceability to the SI:

Capacitance unit is realized at 1 kHz by means of the vertical TL calculable cross capacitor with 0.2 pF nominal capacitance. In [8] it is fixed that the standard deviation (S_0) does not exceed 0.2 $\mu\text{F}/\text{F}$, and the estimation of limit of a relative systematic error (θ_0) does not exceed 0.5 $\mu\text{F}/\text{F}$ when capacitance unit is realized at 1 kHz. Capacitance unit is maintained by the 10 pF group standard that consists of fused silica capacitors of various types – with fused silica dielectric (three different models) and with gas dielectric (KLR type). Capacitors of the group standard are placed in the oil bath at 20 °C or are kept in their own temperature-regulated enclosures.

Appendix B: Uncertainty statements

B.1 Uncertainty statement: CMS, Taiwan

APMP.EM-S7 (100 pF)								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)
1. Realisation of SI farad								
Transfer of DC QHR to 100 k Ω	100	k Ω	0.067	$\mu\Omega/\Omega$	∞	1		0.067
2. 100 kΩ to 1 nF								
Frequency			0.01	$\mu\text{F}/\text{F}$	∞	1		0.010
Bridge resolution			0.03	$\mu\text{F}/\text{F}$	∞	0.5		0.015
Repeatability			0.02	$\mu\text{F}/\text{F}$	3	0.5		0.010
Bridge network			0.01	$\mu\text{F}/\text{F}$	∞	0.5		0.005
Ratio transformer harmonics			0.02	$\mu\text{F}/\text{F}$	∞	0.5		0.010
Ratio of two 1 nF			0.03	$\mu\text{F}/\text{F}$	∞	0.5		0.015
Ratio of two 1 nF			0.031	$\mu\text{F}/\text{F}$	∞	0.5		0.016
3. Measurement of comparison artefact								
Repeatability			0.016	$\mu\text{F}/\text{F}$	5	1		0.016
Temperature correction for 1 nF reference standard			0.005	$\mu\text{F}/\text{F}$	∞	1		0.005
Drift rate for 1 nF reference standard during comparison			0	$\mu\text{F}/\text{F}$	∞	1		0
Ratio transformer			0.02	$\mu\text{F}/\text{F}$	∞	1		0.02
Bridge network			0.01	$\mu\text{F}/\text{F}$	∞	1		0.01
Final Values:	100.000078	pF			3056			0.080

B.2 Uncertainty statement: KIM-LIPI, Indonesia

APMP.EM-S7 (100 pF)								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)
Measurement of comparison artefact								
Mean of n independent measurements	0.54	$\mu\text{F}/\text{F}$	0.066	$\mu\text{F}/\text{F}$	9	1		0.066
Reference Capacitance			0.612	$\mu\text{F}/\text{F}$	>120	1		0.612
Capacitance Drift			0.577	$\mu\text{F}/\text{F}$	∞	1		0.577
Bridge Accuracy			5.774	$\mu\text{F}/\text{F}$	∞	1		5.774
Bridge Accuracy (freq)	1592	Hz	0.744	$\mu\text{F}/\text{F}$	∞	1		0.744
Bridge Resolution			0.003	$\mu\text{F}/\text{F}$	∞	1		0.003
Lead Correction			0.214	$\mu\text{F}/\text{F}$	∞	1		0.214
Reference Temperature	23	$^{\circ}\text{C}$	0.577	$^{\circ}\text{C}$	∞	1.88	$\mu\text{F}/\text{F}/\text{K}$	1.085
Artefact Temperature	23	$^{\circ}\text{C}$	1.732	$^{\circ}\text{C}$	∞	0.01	$\mu\text{F}/\text{F}/\text{K}$	0.017
Measurement Voltage	100	V	4.388	V	∞	0.003	$\mu\text{F}/\text{F}/\text{V}$	0.013
Measurement Frequency	1592	Hz						
Power Line	220	V						
Final Values:	0.54	$\mu\text{F}/\text{F}$			>120			5.99

B.3 Uncertainty statement: KRISS, Korea

Full uncertainty statements are only given below for measurements at 1592 Hz. Where uncertainty components vary for measurements at 1000 Hz, this is indicated in the footnotes.

APMP.EM-S7 (100 pF)								
Quantities	Estimate	Unit	Standard uncertainty	Unit	Effective degrees of freedom	Sensitivity coefficient	Unit	Contribution to the relative standard uncertainty ($\mu\text{F}/\text{F}$)
1. Realisation of SI farad: reference standard								
Reference standard (1)	10	$\mu\text{F}/\text{F}$	0.1	$\mu\text{F}/\text{F}$	13	1		0.1
2. Working standard								
Zerodur capacitor (2)	(10)	$\mu\text{F}/\text{F}$	(0.1)	$\mu\text{F}/\text{F}$				
3. Measurement of comparison artefact								
Mean of 6 independent measurements (5)	0.574	$\mu\text{F}/\text{F}$	0.005	$\mu\text{F}/\text{F}$	11	1		0.005
Bridge resolution	0	$\mu\text{F}/\text{F}$	0.029	$\mu\text{F}/\text{F}$	13	1		0.029
Bridge ratio calibration	0	$\mu\text{F}/\text{F}$	0.02	$\mu\text{F}/\text{F}$	13	1		0.02
Lead correction (3), (5)	-0.113	$\mu\text{F}/\text{F}$	0.023	$\mu\text{F}/\text{F}$	13	1		0.023
Temperature (19.4 \rightarrow 20.0 $^{\circ}\text{C}$) (4)	+0.006	$\mu\text{F}/\text{F}/\text{K}$	0.16	$^{\circ}\text{C}$	11	0.01	$\mu\text{F}/\text{F}/\text{K}$	0.002
Final Values:	0.467	$\mu\text{F}/\text{F}$			17			0.109

Notes:

1. A Zerodur capacitor was used as a reference capacitor of KRISS.
2. The Zerodur capacitor was directly used as a working standard capacitor.
3. The leads for our own bridge were used.
4. Type A uncertainty only.
5. Uncertainty components vary slightly for measurements at 1000 Hz.

B.4 Uncertainty statement: NIM, China

Uncertainty statement for APMP.EM-S7 (100 pF):

Table IV. The uncertainty budget for the measurement		
Item X_i	Sort (A, B)	Uncertainty $u_i(X)$ ($\times 10^{-6}$)
Experimental standard uncertainty	A	0.0115 freedom degrees is 7
Uncertainty from working standard	B	0.11
Uncertainty from leads correction	B	0.003
Uncertainty from ambient temperature	B	0.002
Combined Standard Uncertainty		0.11

B.5 Uncertainty statement: NIMT, Thailand

Mathematical model :

$$C_x = [C_s(1 + T_k \Delta T)(1 + D_r \Delta t) \cdot M_x \cdot M] + C_d + \delta_{res} + \delta_{volt} + \delta_{temp_uuc}$$

Where:

C_x	=	Measured value of unknown capacitor
C_s	=	Capacitance of standard capacitor
$M_x \cdot M$	=	Capacitance bridge ratio
C_d	=	Difference value in between the unknown and the standard capacitor
T_k	=	Temperature coefficient of standard
ΔT	=	Difference in temperature between the calibrated temperature of standard and the ambient temperature
D_r	=	Secular drift of standard
Δt	=	Period of time since last calibration to present
δ_{res}	=	Unknown deviation due to resolution of the capacitance bridge
δ_{volt}	=	Unknown deviation due to measurement voltage
δ_{temp_uuc}	=	Unknown deviation due to ambient laboratory differing from 20 °C

Reference standard capacitors (C_s)

The calibration certificate for the reference standard gives a capacitance value of 10,000127 pF $\cdot (1 \pm 1 \cdot 10^{-6})$ (coverage factor $k=2.1$) at the specified reference temperature of 23,0 °C. The probability distribution is normal then the value of uncertainty taken into account of the uncertainty budget is $u(C_s) = 0,48 \cdot 10^{-6}$.

Temperature (T_k , ΔT)

No correction is made for the temperature coefficient of reference standard. During measurement the reference standard must be kept in air bath which is temperature $(23,0 \pm 0,3$ °C). The value of $T_k \cdot \Delta T$ is $5 \cdot 10^{-6} / C^\circ \cdot 0,3 C^\circ = 1,5 \cdot 10^{-6}$. The probability distribution is assumed to be rectangular and then the value of uncertainty taken into account of the uncertainty budget is $u(T_k \cdot \Delta T) = 1,5 \cdot 10^{-6} / \sqrt{3} = 0,87 \cdot 10^{-6}$.

Drift of the value of the standard (D_r , Δt)

The drift from the history of reference standard capacitor is $0,8 \cdot 10^{-6}$ within $0,7 \cdot 10^{-6}$. The probability distribution is normal then the value of uncertainty taken into account of the uncertainty budget is $u(D_r \cdot \Delta t) = 0,7 \cdot 10^{-6}$.

Capacitance Bridge ratio ($M_x \cdot M$)

No correction is made for error due to the bridge transformer ratios. It is typically within $\pm 1 \cdot 10^{-6}$ estimated from specification for a ratio of 1. The probability distribution is assumed to be rectangular then the value of uncertainty taken into account of the uncertainty budget is $u(M_x \cdot M) = 1 \cdot 10^{-6} / \sqrt{3} = 0,58 \cdot 10^{-6}$.

Resolution of the capacitance readout (δ_{res})

No correction is made for rounding due to the resolution of the capacitance readout of the bridge. The last significant digit on the value being calibrated corresponds to $\pm 1 \cdot 10^{-6}$. The probability distribution is assumed to be rectangular then the value of uncertainty taken into account of the uncertainty budget is $u(\delta_{res}) = 1 \cdot 10^{-6} / \sqrt{3} = 0,58 \cdot 10^{-6}$.

Measurement voltage (δ_{volt})

The voltage coefficient of a UUC from the specification to be $0,003 \cdot 10^{-6} / V$. No correction is made for the measurement voltage. The applied voltage is $(100 \pm 1$ V). The value of (δ_{volt}) is $0,003 \cdot 10^{-6} / V^\circ \cdot 1V = 0,003 \cdot 10^{-6}$. The probability distribution is assumed to be rectangular and then the value of uncertainty taken into account of the uncertainty budget is $u(\delta_{volt}) = 0,003 \cdot 10^{-6} / \sqrt{3} = 0,0017 \cdot 10^{-6}$.

Ambient laboratory differing from 20 °C (δ_{temp_uuc})

The temperature coefficient of a UUC from the specification to be $0,01 \cdot 10^{-6} / C^\circ$. No correction is made for the temperature coefficient. The ambient laboratory is $(23,0 \pm 2,0$ °C). The maximum value of temperature coefficient is $0,01 \cdot 10^{-6} / C^\circ \cdot 5C^\circ = 0,05 \cdot 10^{-6}$. The probability distribution is assumed to be rectangular and then the value of uncertainty taken into account of the uncertainty budget is $u(\delta_{temp_uuc}) = 0,05 \cdot 10^{-6} / \sqrt{3} = 0,03 \cdot 10^{-6}$.

Measurement (C_d)

The observations are made for the difference between the unknown capacitor and the reference standard from the capacitance bridge readout. The uncertainty due to repeatability, $u(C_d)$ of 5 measurements are calculated and assumed a normal distribution.

Capacitance 100 pF @ 1 kHz

Quantity	Estimate	Standard Uncertainty		Probability Distribution	Effective degree of freedom(γ_i)	Sensitivity Coefficient c_i	Uncertainty Contribution	
		$u(x_i)$					$u(y_i)$	
X_i	x_i	Relative	Absolute				Relative	Absolute
C_s	99,998 73 pF	$0,48 \cdot 10^{-6}$	-	Normal	18	1	$0,48 \cdot 10^{-6}$	-
$T_x \Delta T$	0	$0,35 \cdot 10^{-6}$	-	Rectangular	∞	1	$0,35 \cdot 10^{-6}$	-
$D \Delta t$	$-3,5 \cdot 10^{-6}$	$0,25 \cdot 10^{-6}$	-	Normal	13	1	$0,25 \cdot 10^{-6}$	-
$M_x \cdot M$	1	$0,58 \cdot 10^{-6}$	-	Rectangular	∞	1	$0,58 \cdot 10^{-6}$	-
δ_{res}	0	$0,058 \cdot 10^{-6}$	-	Rectangular	∞	1	$0,058 \cdot 10^{-6}$	-
δ_{volt}	0	-	0,577 V	Rectangular	∞	$0,003 \cdot 10^{-6} / V$	$0,0017 \cdot 10^{-6}$	-
$\delta_{temp\ uuc}$	0	-	2,89 °C	Rectangular	∞	$0,01 \cdot 10^{-6} / ^\circ C$	$0,03 \cdot 10^{-6}$	-
C_d	+0,001 75 pF	-	$0,04 \cdot 10^{-6}$	Normal	4	1	$0,04 \cdot 10^{-6}$	-
C_x	100,000 13 pF				> 100		$0,86 \cdot 10^{-6}$	-

Expanded Uncertainty :

$$U = k \cdot u(C_x) = 2,0 \cdot 0,86 \cdot 10^{-6} = 1,7 \cdot 10^{-6}$$

B.6 Uncertainty statement: NMI, Australia

The uncertainty statements presented below are for the 11th measurement (mean measurement date 27 May 2006). They are typical of the uncertainty statements for each measurement by the pilot laboratory at 1592 Hz.

APMP.EM-S7 (100 pF)								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu F/F$)
1. Realisation of SI farad Calculable Capacitor	0	$\mu F/F$	0.0320	$\mu F/F$	6.4	1		0.0320
2. Working standard (50I) Transformer Ratio	0	$\mu F/F$	0.0039	$\mu F/F$	4078	1.41		0.0055
Bridge voltage coefficient	0	$\mu F/F$	0.0034	$\mu F/F$	7	1.41		0.0048
Bridge loading correction	0	$\mu F/F$	0.0015	$\mu F/F$	5	1.41		0.0021
Bridge balance injection	0	$\mu F/F$	0.0010	$\mu F/F$	3	1.41		0.0014
2-port definition	0	$\mu F/F$	0.0010	$\mu F/F$	3	1.41		0.0014
50I Voltage Coefficient	0	$\mu F/F$	0.0000	$\mu F/F$	5	1		0.0000
Bridge resolution	0	$\mu F/F$	0.0029	$\mu F/F$	∞	1.41		0.0041
Extrapolation (1)	0	$\mu F/F$	0.0088	$\mu F/F$	22	1		0.0088
3. Measurement of artefact Mean of 5 independent measurements (1)	0	$\mu F/F$	0.0023	$\mu F/F$	4	1		0.0023
Bridge resolution (2)	0	$\mu F/F$	0.0029	$\mu F/F$	∞	1.58		0.0046
Lead correction (1)	-0.032	$\mu F/F$	0.0016	$\mu F/F$	∞	1		0.0016
Temperature (1)	19.6	$^\circ C$	0.058	$^\circ C$	246	0.0065	$\mu F/F/K$	0.0004
Final Values:	-0.032	$\mu F/F$			9			0.035

Notes:

- These uncertainties may vary slightly from measurement to measurement.
- In measuring the 100 pF artefact, the bridge resolution is applied on four occasions, two of which have a weight of 0.5.

B.7 Uncertainty statement: NMIJ/AIST, Japan

APMP.EM-S7 (100 pF)								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)
Realisation of SI farad: reference standard 100 pF capacitance standard based on a quantized Hall resistance (QHR) (1),(2)	-0.262	$\mu\text{F}/\text{F}$	0.033	$\mu\text{F}/\text{F}$	1828	1		0.033
Measurement of comparison artefact Mean of 5 independent measurements	0.723	$\mu\text{F}/\text{F}$	0.004	$\mu\text{F}/\text{F}$	4	1		0.004
Lead correction (3)	-0.040	$\mu\text{F}/\text{F}$	0.012	$\mu\text{F}/\text{F}$	∞	1		0.012
Temperature correction: (23 °C \rightarrow 20 °C) (4)	0.005	$\mu\text{F}/\text{F}$	0.005	$\mu\text{F}/\text{F}$	∞	1		0.005
Measurement voltage: 100 Vrms (5)			0.1	V	∞	0.003	$\mu\text{F}/\text{F}/\text{V}$	0.0003
Measurement frequency: 10000/2 π Hz (5)			0.005	Hz	∞	0.0002	$\mu\text{F}/\text{F}/\text{Hz}$	0.000001
Final Values:	0.426	$\mu\text{F}/\text{F}$			2277			0.036

Notes:

1. Latest value of the von Klitzing constant of $R_K = 25.812\,807\,449\text{ k}\Omega$ with a relative standard uncertainty of 3.3×10^{-9} was used [9].
2. Details of uncertainties are described in [10].
3. Leads effect was estimated by measuring the relative change of capacitance with changing the length of leads.
4. The temperature coefficient of capacitance with respect to changes in ambient laboratory temperature was measured to be $0.0085\text{ }\mu\text{F}/\text{F}/\text{K}$ for Capacitor A (10 pF) and $-0.0018\text{ }\mu\text{F}/\text{F}/\text{K}$ for Capacitor B (100 pF).
5. Type B uncertainty only.

B.8 Uncertainty statement: NMISA, South Africa

APMP.EM-S7 (100 pF at 1 kHz, 10 V)											
UNCERTAINTY BUDGET MATRIX (UBM)						Certificate No DCLF/C-1259					
Reference: Guide to the Expression of Uncertainty in Measurement, issued by BIPM, IEC, IFCC, ISO, IUPAC, IUPAP, OIML - ISO 1995 (ISBN 92-67-10188-9)											
Description	Calibration of 100 pF Capacitor vs 100 pF reference in substitution method with AH2500A bridge	Type & Serial Number	100 pF, AH 11A, #01350	Range	100 pF, 1 kHz, 10 V						
Mathematical Model $\Delta C_x = \Delta C_{s_{\text{Read}}} - \Delta C_{s_{\text{Read}}} + \Delta C_{s_{\text{Cert}}} + \Delta C_{R_{\text{es}}} + \Delta C_{s_{\text{Cert}}} + \Delta C_{s_{\text{Drift}}} + \Delta C_{s_{\text{Volt}}} + \Delta C_{TCC} + \Delta C_{PLF}$											
Symbol	Input Quantity (Source of Uncertainty) (X_i)	Estimated Input Quantity (x_i)	Estimated Uncertainty	Unit	Probability Distribution (N, R, T, U)	Standard Uncertainty $U(x_i)$	Sensitivity Coefficient C_i	Unit	Standard Uncertainty Contribution $U_i(y)$	Degrees of Freedom ν	
$\Delta C_{s_{\text{Read}}} - \Delta C_{s_{\text{Read}}}$	Average of 29 pairs of readings	-0.4080	0.0005	$\mu\text{F}/\text{F}$	Normal k = 1	1.00	4.668E-04	1.000E+00	4.668E-04	28.00	
$\Delta C_{R_{\text{es}}}$	Reading resolution of the AH2500A (in % mode)	0.000	0.001	$\mu\text{F}/\text{F}$	Triangular $\sqrt{6}$	2.45	4.082E-04	1.000E+00	4.082E-04	infinite	
$\Delta C_{s_{\text{Cert}}}$	Calibration of the reference (BIPM cert. no. 51)	0.910	0.050	$\mu\text{F}/\text{F}$	Normal k = 1	1.00	5.000E-02	1.000E+00	5.000E-02	infinite	
$\Delta C_{s_{\text{Drift}}}$	Drift of the standard since last calibration	0.009	0.003	$\mu\text{F}/\text{F}$	Normal k = 1	1.00	3.000E-03	1.000E+00	3.000E-03	infinite	
$\Delta C_{s_{\text{Volt}}}$	Voltage coefficient of capacitance of reference standard (no contribution)	0.000	0.000	$\mu\text{F}/\text{F}$	Rectangular $\sqrt{3}$	1.73	0.000E+00	1.000E+00	0.000E+00	infinite	
$\Delta C_{s_{\text{Volt}}}$	Voltage coefficient of capacitance of unit under test (no contribution)	0.000	0.000	$\mu\text{F}/\text{F}$	Rectangular $\sqrt{3}$	1.73	0.000E+00	1.000E+00	0.000E+00	infinite	
ΔC_{TCC}	Corrections for temperature influences	0.000	0.030	$\mu\text{F}/\text{F}$	Rectangular $\sqrt{3}$	1.73	1.732E-02	1.000E+00	1.732E-02	infinite	
ΔC_{PLF}	Corrections for powerline fluctuations	0.000	0.001	$\mu\text{F}/\text{F}$	Rectangular $\sqrt{3}$	1.73	5.774E-04	1.000E+00	5.774E-04	infinite	
Value of the measurand (deviation from nominal)		0.511		$\mu\text{F}/\text{F}$							
Combined Standard Uncertainty						5.301E-02	$\mu\text{F}/\text{F}$	ν_{eff}	infinite		
Expanded Uncertainty						Level of Confidence	68,27 %	K = 1	5.30E-02	$\mu\text{F}/\text{F}$	K = 1.00
Absolute value		100.000051 pF									
Absolute uncertainty		5.3E-06 pF									

B.9 Uncertainty statement: NPL, India

The following uncertainty statements are those for measurements at 1592 Hz. Uncertainty statements for measurements at 1000 Hz differ where indicated.

APMP.EM-S7 (100 pF, measured at 10 V)								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)
1. Realisation of SI farad: reference standard								
Value of reference standard (1)	9.9999923	pF	0.3	$\mu\text{F}/\text{F}$	400	1		0.3
Temperature correction	25.0	$^{\circ}\text{C}$	0.05	$\mu\text{F}/\text{F}$		1		0.05
Bridge Transformer Ratio	4×10^{-7}		0.05	10^{-6}		1		0.05
Drift in Standards	2	years	0.2	$\mu\text{F}/\text{F}$		1		0.2
Temp Hysteresis	1	$^{\circ}\text{C}$	0.01	$\mu\text{F}/\text{F}$		1		0.01
Bridge resolution	0.04	$\mu\text{F}/\text{F}$	0.02	$\mu\text{F}/\text{F}$		1		0.02
3. Measurement of comparison artefact								
Mean of n independent measurements (1)	99.999932	pF	0.01	$\mu\text{F}/\text{F}$	8	1		0.01
Lead correction	0	$\mu\text{F}/\text{F}$	0	$\mu\text{F}/\text{F}$				0
Final Values: (1)	99.999932				1028			0.40

APMP.EM-S7 (100 pF, measured at 100 V)								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)
1. Realisation of SI farad: reference standard								
Value of reference standard (1)	99.999931	pF	0.4	$\mu\text{F}/\text{F}$	500	1		0.4
Temperature correction	25.0	$^{\circ}\text{C}$	0.05	$\mu\text{F}/\text{F}$		1		0.05
Bridge calibration	0.1		1	10^{-6}	700	1		1
Drift in Standards	2	years	0.2	$\mu\text{F}/\text{F}$		1		0.2
Temp Hysteresis	1	$^{\circ}\text{C}$	0.01	$\mu\text{F}/\text{F}$		1		0.01
Bridge resolution	0.02	$\mu\text{F}/\text{F}$	0.01	$\mu\text{F}/\text{F}$		1		0.02
Voltage Difference	90	V	0.1	$\mu\text{F}/\text{F}$		1		0.1
3. Measurement of comparison artefact								
Mean of n independent measurements (1)	99.999933	pF	0.02	$\mu\text{F}/\text{F}$	8	1		0.02
Lead correction	0	$\mu\text{F}/\text{F}$	0	$\mu\text{F}/\text{F}$				0
Final Values: (1)	99.999933				840			1.05

Notes:

1. Indicates those values that differ for measurements at a frequency of 1000 Hz.

B.10 Uncertainty statement: SCL, Hong Kong

APMP.EM-S7 (100 pF)									
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)	
1. Realisation of SI farad: reference standard									
Value of reference standard	99.9981	pF	1.5	$\mu\text{F}/\text{F}$	100	1			1.5
Extrapolation to mean measurement date	99.9979	pF	1.3	$\mu\text{F}/\text{F}$	100	1			1.3
Temperature correction	0	$^{\circ}\text{C}$	0.2	K	100	2	$\mu\text{F}/\text{F}/\text{K}$		0.4
3. Measurement of comparison artefact									
Mean of 5 independent measurements	100.00020	pF	0.05	$\mu\text{F}/\text{F}$	5	1			0.05
Bridge resolution	0	$\mu\text{F}/\text{F}$	0.29	$\mu\text{F}/\text{F}$	50	1			0.29
Lead correction	0	$\mu\text{F}/\text{F}$	0.06	$\mu\text{F}/\text{F}$	50	1			0.06
Temperature	23.0	$^{\circ}\text{C}$	1.73	K	50	0.01	$\mu\text{F}/\text{F}/\text{K}$		0.0173
Measurement voltage	7.5	V	53.4	V	50	0.003	$\mu\text{F}/\text{F}/\text{V}$		0.1602
Final Values:					223				2.1

B.11 Uncertainty statement: SIRIM, Malaysia

APMP.EM-S7 (100 pF)									
Quantity	Identifier	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)
1. Reference Standard									
Assigned Value of Ref. Cap.	C_{RefBIPM}	99.999530	pF	0.050	$\mu\text{F}/\text{F}$	50	1		0.050
Transportation effects	$\delta C_{\text{RefTransport}}$	-	pF	0.156	$\mu\text{F}/\text{F}$	∞	1		0.156
Temp. coefficient of Ref. Cap.	$\delta C_{\text{RefTambient}}$	-	pF	0.003	$\mu\text{F}/\text{F}$	∞	1		0.003
Temp. hysteresis of Ref. Cap.	$\delta C_{\text{RefThysteresis}}$	-	pF	0.029	$\mu\text{F}/\text{F}$	∞	1		0.029
Voltage coefficient of Ref. Cap.	$\delta C_{\text{RefTestvoltage}}$	-	pF	0.000	$\mu\text{F}/\text{F}$	∞	1		0.000
Mains line coeff. of Ref. Cap.	$\delta C_{\text{RefMainsvoltage}}$	-	pF	0.000	$\mu\text{F}/\text{F}$	∞	1		0.000
Change in the value of Ref. Cap with time	$\delta C_{\text{RefTime}}$	-	pF	0.662	$\mu\text{F}/\text{F}$	∞	1		0.662
2. Measurement of comparison artefact									
Mean bridge readings	$\text{Decade}_{\text{Mean}}$	0.018720	pF	0.362	$\mu\text{F}/\text{F}$	9	1		0.362
Bridge calibration	$\Delta\text{Bridge}_{\text{Corr}}$	-0.018099	pF	0.362	$\mu\text{F}/\text{F}$	9	1		0.362
Bridge GR 1615 resolution	δ_{resl}	-	pF	0.029	$\mu\text{F}/\text{F}$	∞	1		0.029
Lead Correction	δX_{lead}	-	pF						
Ambient Temperature		22.5	$^{\circ}\text{C}$			∞	1.00E-06		0.003
Correction to temp differing from 20 deg. C	$\Delta\text{TempCorr}$	-0.0000025	pF	0.003	$\mu\text{F}/\text{F}$	∞	1.00E-06		0.000
Measurement voltage		10	V			∞	3.00E-07		0.000
Measurement frequency		1000	Hz						
Final Values:		100.00015	pF			139			0.853

Notes:

- $C_x = C_{\text{Ref}} + \text{Decade}_{\text{Mean}} + \Delta\text{Bridge}_{\text{Corr}} + \delta X_{\text{Tambient}} + \delta X_{\text{testvoltage}} + \delta_{\text{resl}} + \delta X_{\text{lead}}$
- $C_{\text{ref}} = C_{\text{RefBIPM}} + \delta C_{\text{RefTambient}} + \delta C_{\text{RefThysteresis}} + \delta C_{\text{RefTestvoltage}} + \delta C_{\text{RefMainsvoltage}} + \delta C_{\text{RefTime}} + \delta C_{\text{RefTransport}}$

B.12 Uncertainty statement: SPRING, Singapore

Uncertainty statements for measurements at 1592 Hz are given below. Uncertainty statements for measurements at 1000 Hz differ only in the uncertainty component relating to repeatability.

SPRING								
UNCERTAINTY STATEMENT : APMP.EM-S7 (100 pF @ 1592 Hz)								
Capacitor A : Serial Number 01350								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective degrees of freedom	Sensitivity coefficient	Unit	Contribution to the relative standard uncertainty ($\mu\text{F}/\text{F}$)
1 Reference Standard								
1.1 Realisation of SI farad								
1.1.2 Reference standard calibration uncertainty	0.90	$\mu\text{F}/\text{F}$	0.45	$\mu\text{F}/\text{F}$	∞ (7)	1		0.45
1.2 Derivation of value of Reference Standard								
1.2.1 Stability (1)	0.31	$\mu\text{F}/\text{F}$	0.18	$\mu\text{F}/\text{F}$	∞ (7)	1		0.18
1.2.2 Chassis temperature (2)	30.06	$^{\circ}\text{C}$	0.68	$^{\circ}\text{C}$	∞ (7)	0.01	$\mu\text{F}/\text{F}/^{\circ}\text{C}$	0.0039
1.2.3 Measurement voltage (3)	10	V	0.17	V	∞ (7)	0.003	$\mu\text{F}/\text{F}/\text{V}$	0.0000
3 Measurement of comparison artefact								
3.1 Bridge calibration (4)	0.40	$\mu\text{F}/\text{F}$	0.23	$\mu\text{F}/\text{F}$	∞ (7)	1		0.23
3.2 Bridge resolution	0.010	$\mu\text{F}/\text{F}$	0.0058	$\mu\text{F}/\text{F}$	∞ (7)	1		0.0058
3.3 Repeatability	0.031	$\mu\text{F}/\text{F}$	0.010	$\mu\text{F}/\text{F}$	9	1		0.010
3.4 Measurement Conditions								
3.4.1 Ambient temperature (5)	23	$^{\circ}\text{C}$	0.58	$^{\circ}\text{C}$	∞ (7)	0.01	$\mu\text{F}/\text{F}/^{\circ}\text{C}$	0.0033
3.4.2 Measurement voltage (3)	10	V	0.17	V	∞ (7)	0.003	$\mu\text{F}/\text{F}/\text{V}$	0.0000
3.4.3 Measurement frequency (6)	1592	Hz	-		∞ (7)	-		-
Final Values : (combined standard uncertainty)								0.6

Notes :

1 due to drift of reference standard

2 reference standard calibrated at chassis temperature of 28.9 $^{\circ}\text{C}$

3 AC test signal voltage; 10 V \pm 3 %, reference values were calibrated at 10 V

4 includes stability, non-linearity, temperature coefficient, leads

5 ambient temperature was 23 \pm 1.0 $^{\circ}\text{C}$

6 frequency was derived by synthesis from a frequency primary standard so effect of frequency uncertainty is insignificant

7 type B uncertainty, assuming rectangular distribution

B.13 Uncertainty statement: VNIIM, Russia

APMP.EM-S7 (100 pF)								
Quantity	Estimate	Unit	Standard uncertainty	Unit	Effective DOF	Sensitivity coefficient	Unit	Contribution to rel. std. unc. ($\mu\text{F}/\text{F}$)
1. Realisation of SI farad: VNIIM calculable capacitor								
Geometrical imperfections	0.2	pF	0.08	$\mu\text{F}/\text{F}$	13	1		0.08
Laser interferometer	0	$\mu\text{F}/\text{F}$	0.03	$\mu\text{F}/\text{F}$	8	1		0.03
Transformer bridge	0	$\mu\text{F}/\text{F}$	0.06	$\mu\text{F}/\text{F}$	13	1		0.06
Insufficient sensitivity	0	$\mu\text{F}/\text{F}$	0.09	$\mu\text{F}/\text{F}$	6	1		0.09
Repeatability	0	$\mu\text{F}/\text{F}$	0.10	$\mu\text{F}/\text{F}$	6	1		0.10
2. Working standard (10 pF) (1)								
Build-up from calculable capacitor	0	$\mu\text{F}/\text{F}$	0.04	$\mu\text{F}/\text{F}$	8	1		0.04
Extrapolation to mean measurement date	0	$\mu\text{F}/\text{F}$	0.02	$\mu\text{F}/\text{F}$	50	1		0.02
Bridge calibration	0	$\mu\text{F}/\text{F}$	0.02	$\mu\text{F}/\text{F}$	13	1		0.02
Temperature correction	0	$\mu\text{F}/\text{F}$	0.03	$\mu\text{F}/\text{F}$	20	1		0.03
3. Measurement of comparison artefact								
Mean of 7 independent measurements	0.27	$\mu\text{F}/\text{F}$	0.016	$\mu\text{F}/\text{F}$	6	1		0.016
Ratio calibration	0.12	$\mu\text{F}/\text{F}$	0.08	$\mu\text{F}/\text{F}$	6	1		0.08
Bridge resolution	0	$\mu\text{F}/\text{F}$	0.02	$\mu\text{F}/\text{F}$	13	1		0.02
Lead correction	-0.018	$\mu\text{F}/\text{F}$	0.005	$\mu\text{F}/\text{F}$	20	1		0.005
Temperature correction	-0.004	$\mu\text{F}/\text{F}$	0.1	$^{\circ}\text{C}$	13	0.01	$\mu\text{F}/\text{F}/\text{K}$	0.001
Final Values: (2)	0.37	$\mu\text{F}/\text{F}$			39			0.198

Notes:

- The group standard for maintenance of the national unit of capacitance.
- Calculated value of effective degrees of freedom is truncated to the next lower integer.

Appendix C: Optional measurements: Dissipation factor

Reporting of the dissipation factor was optional. The capacitor is modelled as an ideal capacitor, of capacitance C , in parallel with an ideal resistor, of conductance G . The admittance of the capacitor is therefore $Y = G + j\omega C$ and the dissipation factor $D = G/\omega C$.

Three participants made measurements of the dissipation factor. Results are shown in Table A - 2.

Participant	Measurement Voltage (V)	$f = 1000 \text{ Hz}$		$f = 1592 \text{ Hz}$	
		D (μrad)	$U_{95\%}$ (μrad)	D (μrad)	$U_{95\%}$ (μrad)
NPLI	10	0	3	0	3
	100	0	3	0	5
KRISS	10	0.550	0.009	0.550	0.009
VNIIM	9.85	1.5	1.5	-	-

Table A - 2 Dissipation factor measurements.

Appendix D: References

- [1] Mutual Recognition Arrangement “Mutual Recognition of National Measurement Standards and of Calibration and Measurement Certificates Issued by National Metrology Institutes - Arrangement Drawn up by the International Committee of Weights and Measures under the Authority Given to it in the Metre Convention.” http://www.bipm.org/utls/en/pdf/mra_2003.pdf 15 January 2007.
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Appendix E: Comparison protocol

The comparison protocol is attached.

Protocol
for
APMP.EM-K4.1
APMP Key Comparison of Capacitance at 10 pF
and
APMP.EM-S7
APMP Supplementary Comparison of Capacitance at 100 pF

Contents

1. Introduction.....	35
2. Travelling Artefacts	35
(a) Description	35
(b) Operation	37
3. Transport of Artefacts.....	37
(a) Customs arrangements	37
(b) Transport case	37
(c) Damage	37
(d) Receipt of travelling standard	37
(e) Measurement Period.....	38
(f) Dispatch of travelling standard.....	38
4. Measurement of the capacitors.....	38
(a) Preparation	38
(b) Laboratory conditions	39
(c) Measurement voltage	39
(d) Measurement frequency.....	39
(e) Measurement leads.....	39
(f) Recorded quantities	39
(g) Temperature dependence of capacitance	39
5. Reporting of results.....	39
(a) General comments.....	39
(b) Results	40
(c) Uncertainty	40
6. Notes	40

7. Comparison costs	41
8. Inquiries	42
Appendix I: Schedule.....	51

11 Introduction

A key comparison of capacitance at 10 pF and a supplementary comparison of capacitance at 100 pF is to be conducted between participating APMP member laboratories. Its aim is to provide participating laboratories with the opportunity to intercompare national standards of capacitance within the Region, and to gain experience and knowledge in this field.

It is proposed that the values from this key comparison in the APMP region be linked to the international key comparison CCEM-K4 carried out between 1994 and 1996. The linking laboratories will be NML CSIRO (Australia), MSL IRL (New Zealand), NIM (China) and VNIIM (Russian Federation).

The National Measurement Laboratory (NML), Australia, will act as the pilot laboratory for the comparison. Dr Leigh Johnson will act as the coordinator. The members of the support group for the comparison are Dr. Sze Wey Chua, SPRING Singapore, Dr Rae Duk Lee, KRISS Korea and Mr Andrew Corney, MSL New Zealand.

It is expected that the comparison will start towards the end of 2003. Each participating laboratory should ensure that the time required for their measurements and for transportation to the next laboratory does not exceed four weeks. It is anticipated that the comparison measurements will be completed within two years.

The circulation of the capacitors will be organised in loops of no more than five laboratories to allow close monitoring of the behaviour of the standard capacitors.

In the event of failure of a standard the pilot laboratory should be informed. The pilot laboratory will consider whether to continue the comparison with the remaining capacitor, substitute an alternative standard or abandon the comparison.

This protocol has been developed according to the Guidelines for CIPM key comparisons, available on the BIPM web site:

<http://www.bipm.fr/pdf/guidelines.pdf>

12 Travelling Artefacts

12.1 Description

The artefacts are a 10 pF and a 100 pF Andeen-Hagerling AH11A fused silica capacitance standard mounted in a single AH1100 capacitance standard frame. Details of the two comparison capacitors are given in Table 3 and the manufacturer's specifications for this type of standard are given in Table 4. The AH1100 frame is a standard width bench-top or rack-mountable frame. Each AH11A capacitance standard includes a temperature-controlled oven that is powered via the AH1100 frame. The frame also monitors internal power voltages and temperatures.

More detailed information on this type of capacitance standard is available on the manufacturers web site:

<http://www.andeen-hagerling.com/ah11a.htm>

The capacitors are fitted with BNC co-axial terminations. Co-axial measuring leads with BNC to MUSA connectors will be supplied with the capacitors, together with MUSA-GR874 adapters and MUSA-BNC adapters.

A power line cord (standard IEC connector to Australian three-pin plug) will be supplied to power the standard. Participants may need an adapter or a power line cord appropriate to their country.

Comparison identifier	P2-APMP.EM-K4.1	P1-APMP.EM-S7
Comparison type	Key	Supplementary
Nominal value of capacitance	10 pF	100 pF
Capacitor identifier	Capacitor A	Capacitor B
Serial number of capacitor	01349	01350

Table 3 Details of the comparison capacitors.

Operating parameters:	
12.1.1.1.1 Power voltage ranges	85 to 115, 102 to 138, 187 to 253 and 204 to 276 volts rms
Power frequency	48 to 440 Hz
Warm up time from power-on	30 minutes
Operating temperature range	10° to 40° C
Maximum allowable applied voltage	250 volts peak
Operating humidity range	0 to 85% relative humidity, non-condensing
Sensitivity of AH11A capacitance standard:	
12.1.1.1.2 Temperature coefficient relative to a change in ambient temperature	0.01 $\mu\text{F}/\text{F}/\text{K}$
12.1.1.1.3 AC voltage coefficient	0.003 $\mu\text{F}/\text{F}/\text{volt rms}$ at 1 kHz
12.1.1.1.4 Sensitivity to power line voltage changes	0.0003 $\mu\text{F}/\text{F}$ per 1% change in power line voltage
12.1.1.1.5 Hysteresis from mechanical shock	0.05 $\mu\text{F}/\text{F}$
12.1.1.1.6 Hysteresis from temperature cycling	0.05 $\mu\text{F}/\text{F}$
12.1.1.1.7 DC voltage coefficient	0.0001 $\mu\text{F}/\text{F}/\text{V}$
Transport information:	
Storage temperature range	-40° to +75° C
AH 1100 frame size	8.9 cm high and 38.1 cm deep behind the front panel.

Total weight of AH1100 frame and two AH11A capacitors	8.4 kg
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Table 4 Manufacturer's specifications for the Andeen-Hagerling AH11A standard capacitor and AH1100 frame.

12.2 Operation

The AH 1100/11A Operation and Maintenance Manual will be included with the shipment. Participants should familiarise themselves with the operation of the standards before proceeding. In particular, the correct line voltage must be selected and a corresponding fuse fitted **before applying power to the unit**.

Measurements should not be taken until the OVEN NOT READY indicator stops blinking. If the OVEN NOT READY indicator continues blinking for more than an hour after applying power to the standard or starts blinking during measurements, please contact the pilot laboratory.

Note that the HIGH and LOW terminals of the capacitors have different properties. Refer to Chapter 2 of the AH 1100/11A Operation and Maintenance Manual for more information.

13 Transport of Artefacts

13.1 Customs arrangements

The artefacts will be transported using an ATA Carnet for customs clearance where possible. A separate comparison loop will be organised for those participants that do not qualify for the ATA scheme.

13.2 Transport case

The capacitors will be transported in an aluminium case. The dimensions of the transport case are 750 mm x 750 mm x 450 mm. The case weighs 27 kg giving a total shipping weight of approximately 36 kg.

Participants are requested to ensure that handling and transport shock is kept to a minimum.

13.3 Damage

Please report to the pilot laboratory any damage of the artefacts or accompanying items.

13.4 Receipt of travelling standard

On receipt of the travelling standard:

1. Inspect the outside of the transport case for any signs of physical damage. A shock monitor is attached to the outside of the transport case. Check that the monitor label has not been activated.
2. Open the transport case and check that the contents are complete (refer to Packing List for list of contents). In particular, please check that the Carnet is with the shipment.
3. Notify **both the pilot laboratory and the sending laboratory** of the receipt of the travelling standards using the Artefact Received Fax Form provided. Fax numbers for each participating laboratory are given in the Participant List.
4. Retain or make a copy of all shipping documentation. Please do not dispose of this documentation until the comparison is complete. **DO NOT** retain the original copy of the carnet.

5. A copy of the AH 1100/11A Operation and Maintenance Manual is included in the shipment. If you have not used this type of standard before, please familiarise yourself with the operation of the standards before proceeding.
6. The AH1100 frame containing the two capacitance standards should be removed from the transport case. Please do not open the AH1100 frame. Please do not remove the AH11A capacitance standards from the frame. Remove the travelling plug from the power line cord receptacle at the back of the bridge. Before applying power to the unit, select the correct line voltage and fit an appropriate fuse, referring to pages 1-5 and 1-6 of the AH 1100/11A Operation and Maintenance Manual.
7. Apply power to the frame and wait until the oven temperature is stable (OVEN NOT READY indicator stops blinking). Typically, the oven will take 20 minutes to stabilise. For the most precise measurements, it is recommended that the standards are left to stabilise for two to three days.

13.5 Measurement Period

The draft comparison schedule allows a total of four weeks for each laboratory. The four week period starts when the travelling artefact arrives in the participant's country and ends when the travelling artefact arrives in the following participant's country. It is anticipated that participants will have at least a two week measurement period.

Arrangements for shipping the artefact to the next scheduled laboratory should be in place before the end of the measurement period. As a courtesy, contact should be made with the next scheduled laboratory regarding shipping, particularly if the anticipated dispatch date is earlier or later than scheduled.

Participants are requested to inform the pilot laboratory if delays to the Schedule have occurred or are likely to occur. If unforeseen circumstances prevent a laboratory from carrying out or completing measurements within the scheduled period, the pilot laboratory will, in most cases, request that the artefacts be sent to the next scheduled laboratory without delay. If time allows, the artefacts will be returned to the laboratory for the completion of measurements at a later date.

13.6 Dispatch of travelling standard

On completion of measurements each participant is requested to ship the travelling standard to the next scheduled laboratory.

Repack the artefact and all accompanying items in the transport case. Please check that the contents are complete (refer to Packing List for list of contents). In particular, please ensure that the carnet travels with the artefact but do **NOT** pack the Carnet inside the transport case.

Addresses for dispatching the artefacts are given in the Participant List.

On dispatch of the travelling standard, notify **both the pilot laboratory and the recipient laboratory** using the Artefact Shipped Fax Form provided. Fax numbers for each participating laboratory are given in the Participant List.

14 Measurement of the capacitors

14.1 Preparation

The artefacts should be unpacked and left to stabilise according to the instructions given in Section 13.4 "Receipt of travelling standard".

14.2 Laboratory conditions

Refer to the manufacturer's specifications listed in Table 4.

14.3 Measurement voltage

The measurement voltage must not exceed a peak value of 250 V.

The preferred measuring voltage for both capacitor is 100 V(rms).

An alternate measuring voltage for the 100 pF capacitor is 10 V(rms).

The manufacturer's specification for the voltage coefficient of the capacitors is 0.003 $\mu\text{F}/\text{F}/\text{V}(\text{rms})$ at 1 kHz. Participants may choose to include this as a source of uncertainty if they use measuring voltages other than those listed above.

14.4 Measurement frequency

The preferred measurement frequency is 1592 Hz ($\omega = 10^4 \text{ rad}\cdot\text{s}^{-1}$). Measurements may be made at a frequency of 1000 Hz instead of, or as well as, 1592 Hz.

14.5 Measurement leads

Participants may use any of the leads and adapters supplied with the capacitors, or may choose to use their own leads. Please note that participants are responsible for determining any necessary corrections for leads or adapters to obtain the capacitance **at the terminals on the AH1100 frame**.

14.6 Recorded quantities

For each measurement, the following quantities should be recorded:

1. the measurement date
2. the applied voltage,
3. the measurement frequency,
4. the measured capacitance,
5. the air temperature in the vicinity of the measuring apparatus and the capacitors, and
6. the chassis temperature and the drift reading (these quantities need not be included in the report but should be noted on the Artefact Shipped Fax Form)

14.7 Temperature dependence of capacitance

The temperature coefficient of capacitance with respect to changes in ambient laboratory temperature is less than 0.01 $\mu\text{F}/\text{F}/\text{K}$ for both capacitors. No corrections should be made for ambient laboratory temperature. Participants may choose to include a component for ambient laboratory temperature in their uncertainty budget if the ambient laboratory temperature differs from 20 °C.

15 Reporting of results

15.1 General comments

A full measurement report in English containing all relevant data and uncertainty estimates is to be forwarded to the coordinator within six weeks of completing measurement of the capacitors. Prompt reporting is encouraged to allow rapid identification of problems with the travelling artefacts. The report should include a description of the measurement method (facilities and

methodology), the traceability to the SI, and the results, associated uncertainty and number of degrees of freedom.

Participants are encouraged to submit their results using the Measurement Report Form. Participants may submit their results in the format of Calibration Certificates normally issued by their laboratory provided the all the required data are either included or attached.

15.2 Results

The capacitance **at the terminals on the AH1100 frame** is to be reported for each capacitor.

The mean measurement date, the measurement frequency and the applied voltage must also be reported for each capacitor.

Details of any corrections that have been applied (for example, bridge corrections or leads corrections) must be given.

All results should be clearly identified with the serial number of the capacitor (refer to Table 3).

15.3 Uncertainty

The uncertainty calculation should be carried out in accordance with the ISO “Guide to the expression of uncertainty in measurement”. All contributions to the uncertainty of measurement should be listed separately in the report and identified as either Type A or Type B uncertainties. The overall uncertainty, as calculated from the individual uncertainties, should be stated. Uncertainties are to be evaluated at the level of one standard uncertainty and the number of degrees of freedom are to be reported. The main uncertainty components are expected to be:

- Experimental standard uncertainty of the mean of n independent measurements (Type A)
- Uncertainty in the primary standard or working standard against which the artefacts are measured (Type B)
- Uncertainty due to leads correction (Type B)

Participants may need to consider the following additional sources of uncertainty, depending on their individual circumstances:

- Uncertainty due to ambient laboratory temperature differing from 20 °C (see Section 14.7) (Type B)
- Uncertainty due to measurement voltage differing from recommended level (see Section 14.3) (Type B)
- Uncertainty due to power line changes (refer to Table 4) (Type B)
- Uncertainty due to frequency (Type B)

Participants may need to include additional sources of uncertainty appropriate to their measurement system.

16Notes

If any laboratory feels that it would have difficulty meeting any of the above requirements, rather than withdraw from the comparison, it should discuss the problem with the coordinator so that satisfactory arrangements can be made. It is expected that amongst participating laboratories, uncertainties will cover a wide range (according to local requirements). This should not be seen as a deterrent to participating in the comparison.

17 Comparison costs

Each participating laboratory is responsible for meeting the costs of its own measurements.

In addition, each participating laboratory is responsible for meeting all costs, and making all arrangements, relating to the transport of the travelling artefact from the time the artefact arrives in their country to the time the artefact arrives in the country of the next participating laboratory. Costs may include (but are not limited to) costs associated with the arrival in the country (eg. customs charges, quarantine fees, broker fees, carrier charges from the port of arrival to the participants laboratory) and costs associated with transporting the artefacts from the participant's laboratory to the international port in the next scheduled country closest to the next participant's laboratory. International carriage is to be by air.

18 Inquiries

All inquiries or communications relating to the comparison should be addressed in the first instance to the comparison co-ordinator, Leigh Johnson.

18.1.1.1 Dr Leigh Johnson

National Measurement Telephone: + 61 2 8467 3529

Institute 18.1.1.3 Fax: + 61 2 8467 3610

P. O. Box 218 E-mail:

18.1.1.1.1 Lindfield

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[leigh.johnson@measurement.gov.](mailto:leigh.johnson@measurement.gov.au)

[au](http://www.measurement.gov.au)

18.1.1.2 AUSTRALIA

An alternative contact for urgent inquiries or communications relating to shipment:

18.1.1.4 Mrs Darien Northcote

National Measurement Telephone: + 61 2 8467 3574

Institute 18.1.1.6 Fax: + 61 2 8467 3719

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[ov.au](http://www.measurement.gov.au)

18.1.1.5 AUSTRALIA

Further information and progress reports for the comparison will be available on the NML website at:

<http://www.measurement.gov.au/>

Appendix II: Participants

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M2	KRISS (KOREA)	<p>Contact Person: Dr Rae Duk Lee</p> <p>E-mail: rdlee@kriss.re.kr</p> <p>Telephone Number: +82 42 868 5150</p> <p>Fax Number: +82 42 868 5018</p>

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M7	<p style="text-align: center;">NPL</p> <p style="text-align: center;">(INDIA)</p>	<p>Contact Person: A K Saxena</p> <p>E-mail: aksaxena@mail.nplindia.ernet.in</p> <p>Telephone Number: +91 11 2574 26 10 or 11 or 12: Ext 2291, 2211, 2259</p> <p>Fax Number: +91 11 2572 6938 or 91 11 2572 6952</p> <p>Delivery Address: National Physical Laboratory (NPL) Director National Physical Laboratory Dr K S Krishnan Rd New Dehli 110012 INDIA</p>

M8	<p data-bbox="252 300 341 331">NIMT</p> <p data-bbox="197 405 395 436">(THAILAND)</p>	<p data-bbox="549 241 1118 273">Contact Person: Mrs Ajchara Charoensook</p> <p data-bbox="660 300 1027 331">E-mail: ajchara@nimt.or.th</p> <p data-bbox="496 351 979 383">Telephone Number: +66 2 248 2181</p> <p data-bbox="580 405 979 436">Fax Number: +66 2 248 4485</p> <p data-bbox="528 456 1417 488">Delivery Address: National Institute of Metrology Thailand (NIMT)</p> <p data-bbox="778 510 1241 542">Department of Electrical Metrology</p> <p data-bbox="778 564 1246 595">Ministry of Science and Technology</p> <p data-bbox="778 618 1034 649">75/7 Rama VI Road</p> <p data-bbox="778 672 1114 703">Thungphayathai, Rajthevi</p> <p data-bbox="778 725 979 757">Bangkok 10400</p> <p data-bbox="778 779 943 810">THAILAND</p>
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M9	<p data-bbox="213 994 379 1025">NML, CSIR</p> <p data-bbox="161 1099 432 1131">(SOUTH AFRICA)</p>	<p data-bbox="549 936 995 967">Contact Person: Mr Louis Marais</p> <p data-bbox="660 994 1059 1025">E-mail: ELMarais@csir.co.za</p> <p data-bbox="496 1046 995 1077">Telephone Number: +27 12 841 3013</p> <p data-bbox="580 1099 995 1131">Fax Number: +27 12 841 4458</p> <p data-bbox="528 1151 1374 1182">Delivery Address: National Metrology Laboratory (NML), CSIR</p> <p data-bbox="778 1205 874 1236">Build 5</p> <p data-bbox="778 1258 1273 1290">CSIR, National Metrology Laboratory</p> <p data-bbox="778 1312 1018 1344">Meiring Naude Rd</p> <p data-bbox="778 1366 922 1397">Brummeria</p> <p data-bbox="778 1420 879 1451">Pretoria</p> <p data-bbox="778 1473 836 1505">0001</p> <p data-bbox="778 1527 1007 1559">SOUTH AFRICA</p>
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M14		<p>Contact Person: Dr Laurie Christian</p>
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Appendix I: Schedule

Measurement Period	Laboratory	Economy	Receive Date	Ship Date	Report Date
M0	NMI	Australia		12 January, 2004	
M1	NMIJ	Japan	19 January, 2004	09 February, 2004	22 March, 2004
M2	KRISS	Korea	16 February, 2004	08 March, 2004	19 April, 2004
M3	PSB	Singapore	15 March, 2004	05 April, 2004	17 May, 2004
M4	CMS/ITRI	Chinese Taipei	12 April, 2004	03 May, 2004	14 June, 2004
M5	NMI	Australia	10 May, 2004	31 May, 2004	
M6	CPEM 2004: 27 June - 2 July				
M7	NPL	India	05 July, 2004	26 July, 2004	06 September, 2004
M8	NIMT	Thailand	02 August, 2004	23 August, 2004	04 October, 2004
M9	NML, CSIR	South Africa	30 August, 2004	20 September, 2004	01 November, 2004
M10	NMI	Australia	27 September, 2004	18 October, 2004	
M11	SIRIM	Malaysia	25 October, 2004	15 November, 2004	27 December, 2004
M12	HKGSCS	Hong Kong	22 November, 2004	13 December, 2004	24 January, 2005
M13	LIPI	Indonesia	20 December, 2004	10 January, 2005	21 February, 2005
M14	IRL	New Zealand	17 January, 2005	07 February, 2005	21 March, 2005
M15	NMI	Australia	14 February, 2005	07 March, 2005	
M16	NIM	China	14 March, 2005	04 April, 2005	16 May, 2005
M17	Extra time for custom clearance to VNIIM				
M18	VNIIM	Russian Federation	09 May, 2005	30 May, 2005	11 July, 2005
M19	NMI	Australia	06 June, 2005		

Additional Schedule:

Measurement Period	Laboratory	Economy	Receive Date	Ship Date	Report Date
M20	NMI	Australia		20 January 2006	
M21	KRISS	Korea	27 January 2006	17 February 2006	31 March 2006
M22	SPRING	Singapore	24 February 2006	17 March 2006	28 April 2006
M23	NMIJ/AIST	Japan	24 March 2006	14 April 2006	26 May 2006
M24	CMS/ITRI	Chinese Taipei	21 April 2006	12 May 2006	23 June 2006
M25	NMI	Australia	19 May 2006		